

11th International Summer School on RF MEMS and RF Microsystems
IHP, Frankfurt (Oder) – Germany June 22nd – 26th 2015

Basics of mm-wave Measurements

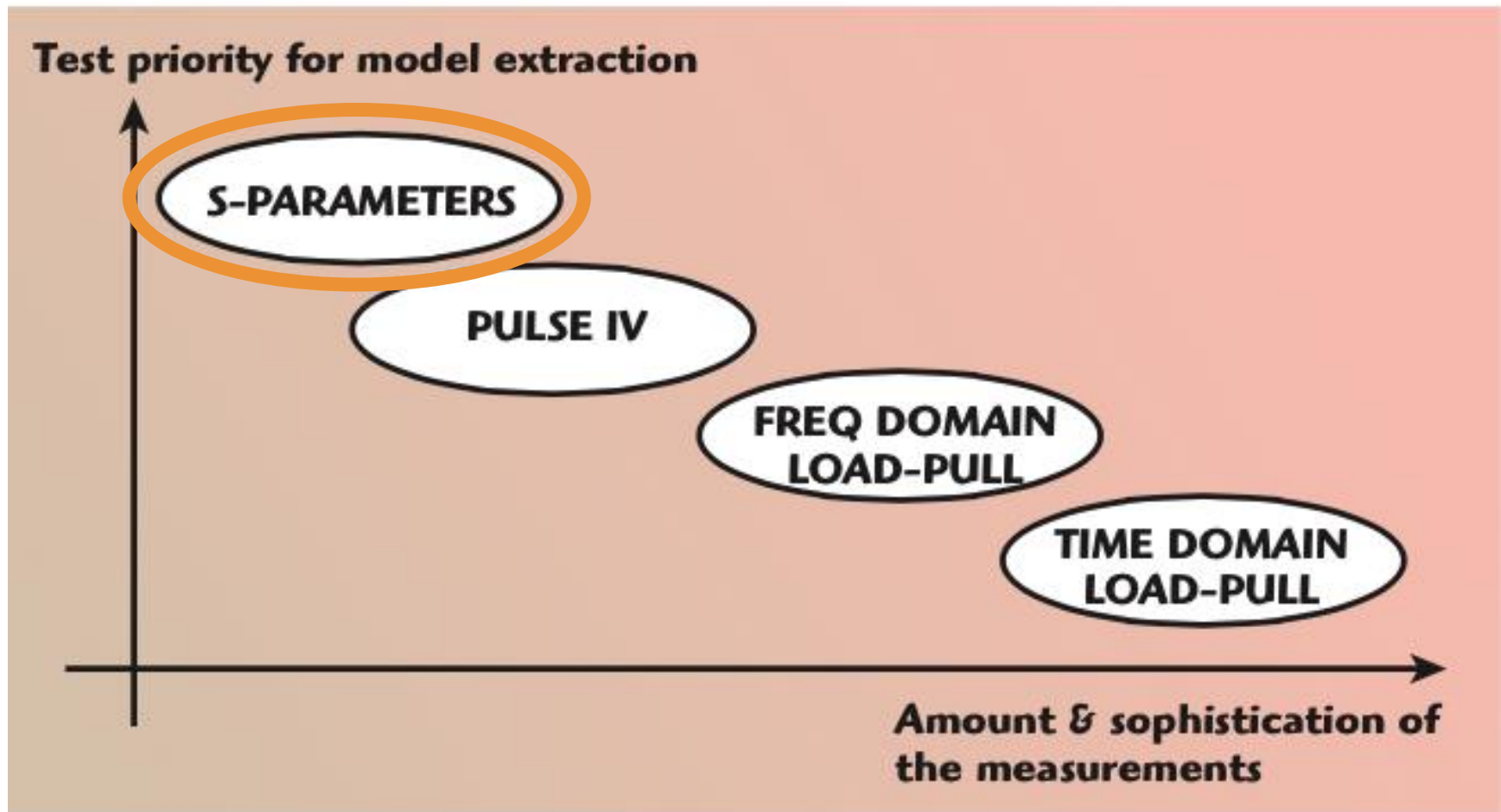
Dr. Andrej Rumiantsev

Director RF Technologies MPI Corporation

Outline

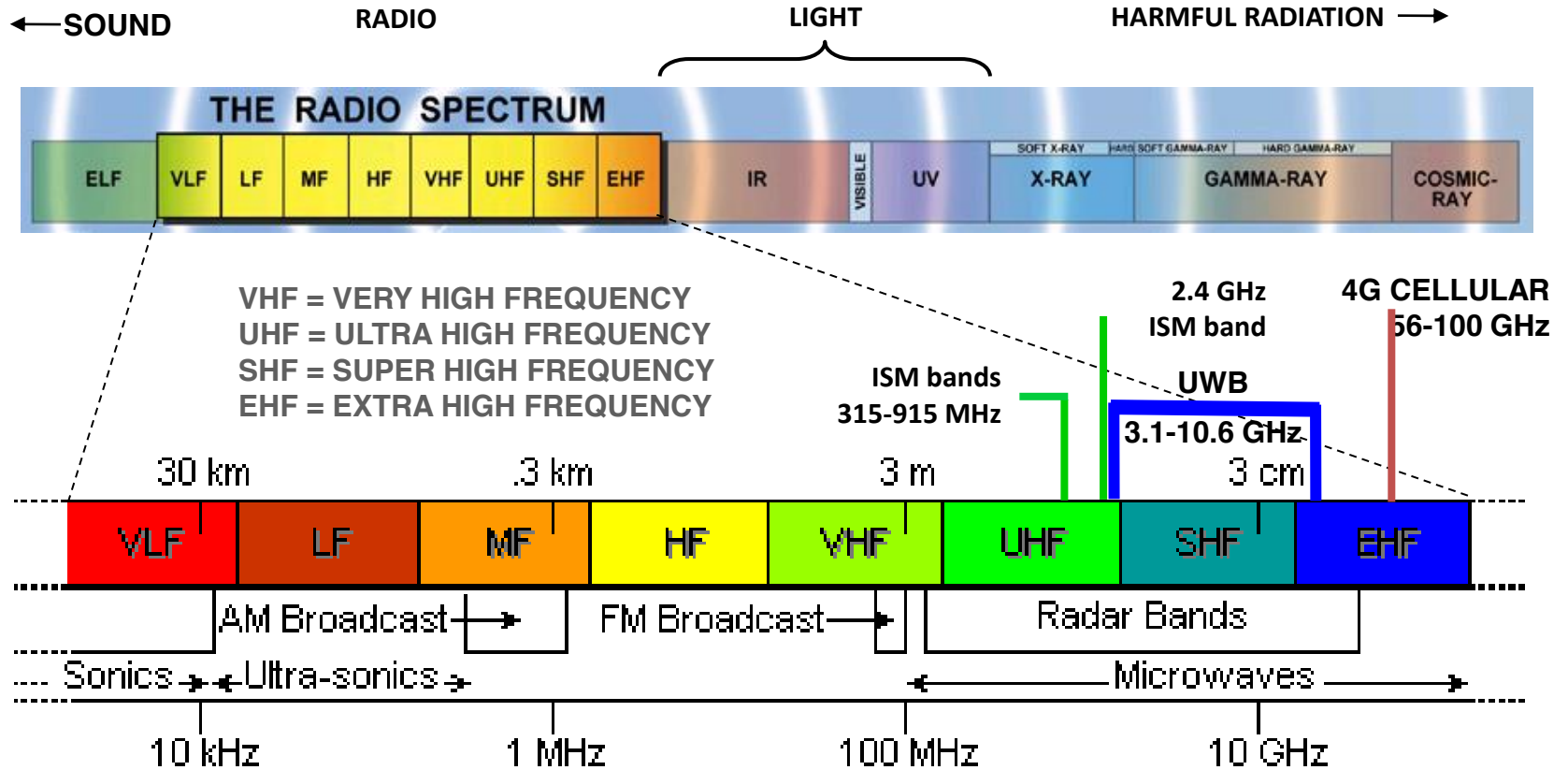
- Introduction
- S-parameters Basics
- Measurement of S-parameters
- VNA Building Blocks
- Instrumentation

Importance of RF-Measurements



T. Gasseling , MW Journal, 03-2012

Where Do RF & Microwaves Start?



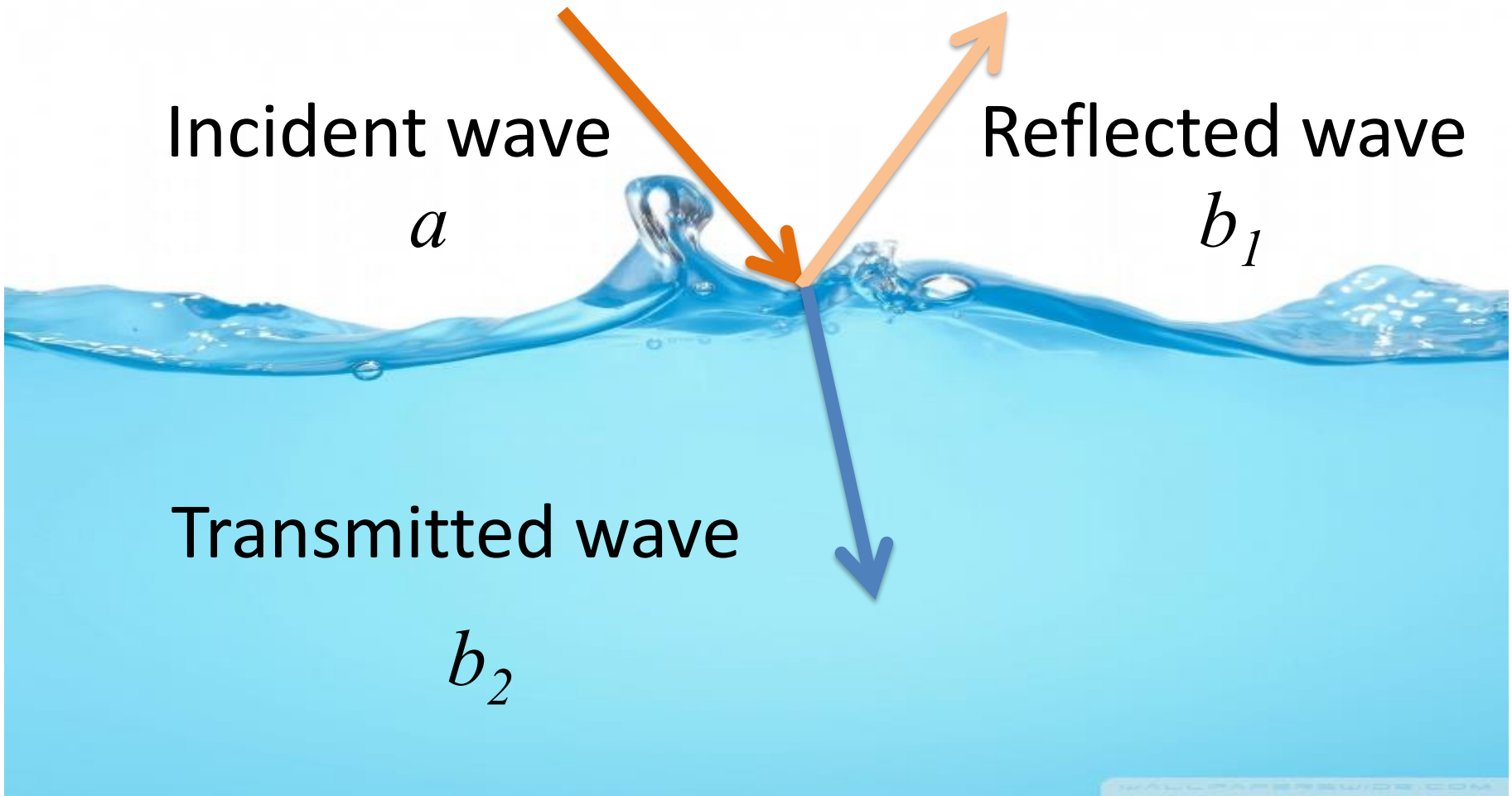
10 GHz ~ 3 cm wave length

Source: JSC.MIL

Outline

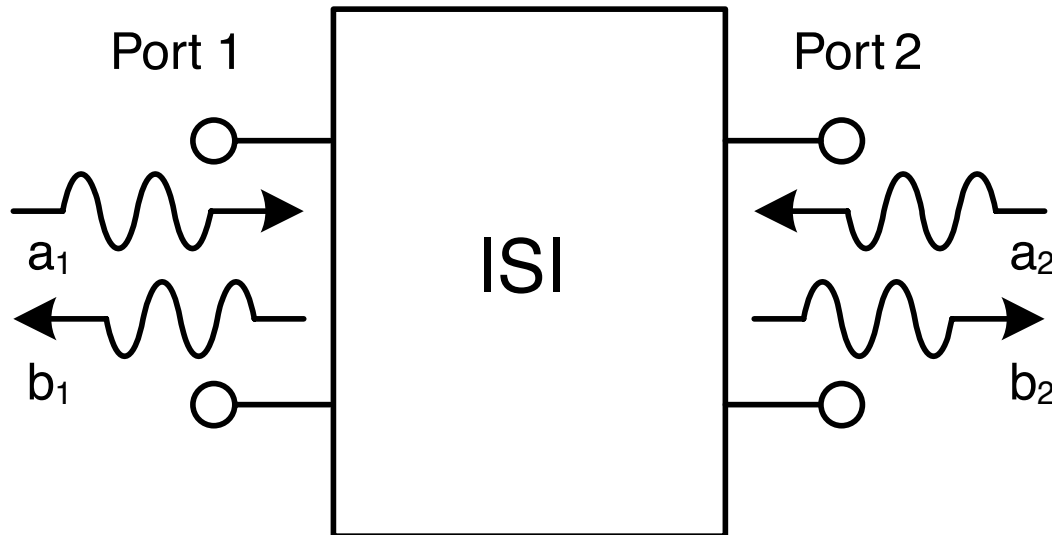
- Introduction
- S-parameters Basics
- Measurement of S-parameters
- VNA Building Blocks
- Instrumentation

..its all about Waves



... over S-Parameters

- Relationship of:
 - incident (a) and reflected/transmitted (b) waves at device terminals



Why S-Parameters

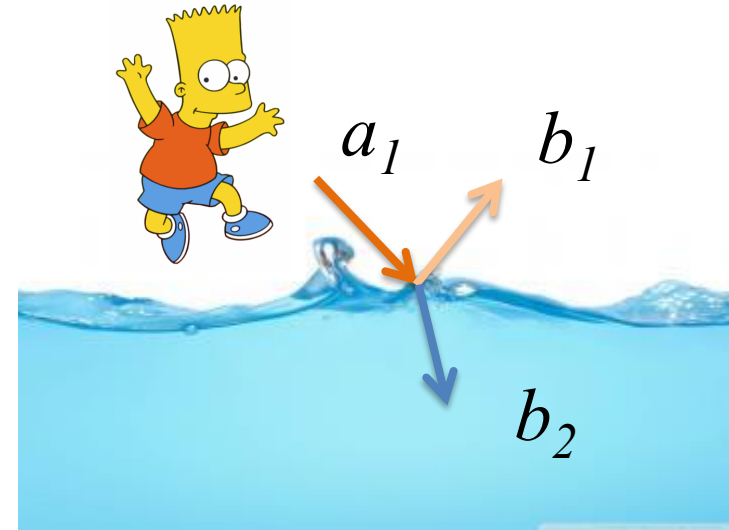
- Wave quantities are easy to measure
- Can be converted to Z -, Y -, H - and other parameters

$$S_{ii} = \frac{b_i}{a_i} = \frac{Z_{DUT} - Z_{REF}}{Z_{DUT} + Z_{REF}}$$

S-Parameter Matrix

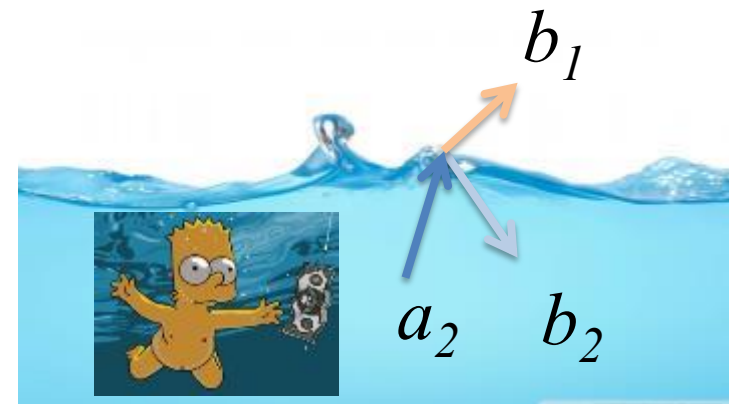
- Forward direction

$$S_{11} = b_1/a_1 \quad S_{21} = b_2/a_1$$



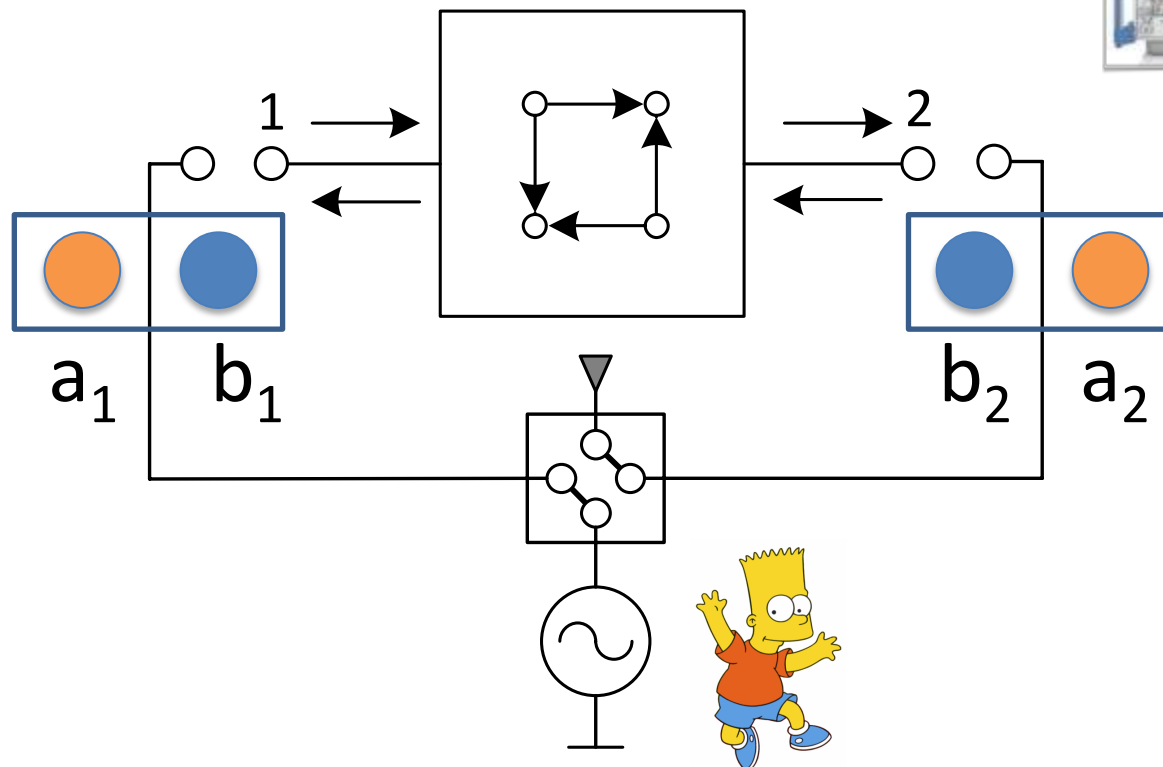
- Reverse direction

$$S_{22} = b_2/a_2 \quad S_{12} = b_1/a_2$$



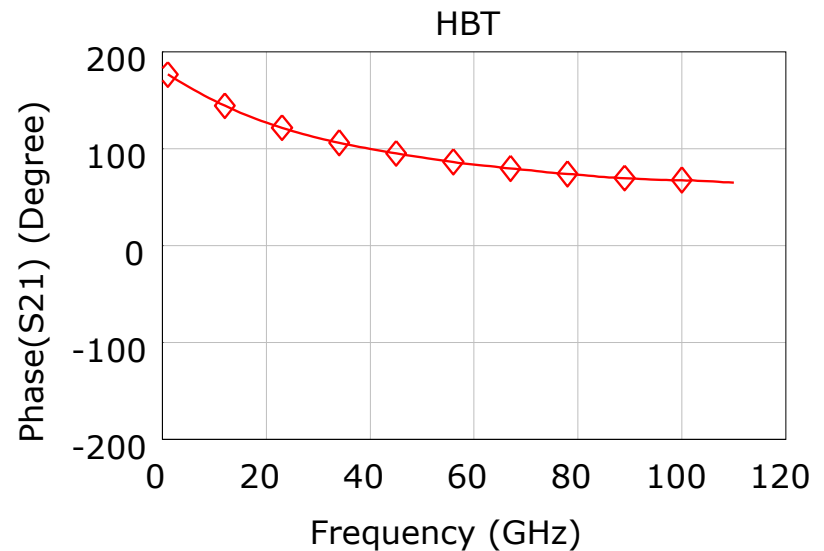
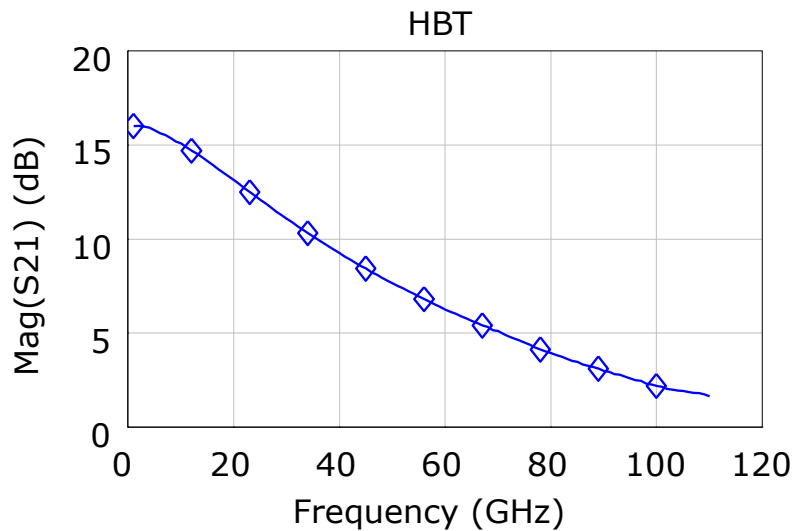
S-Parameters Measured by VNA

- Vector Network Analyzer (VNA)

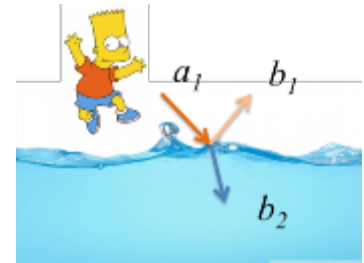
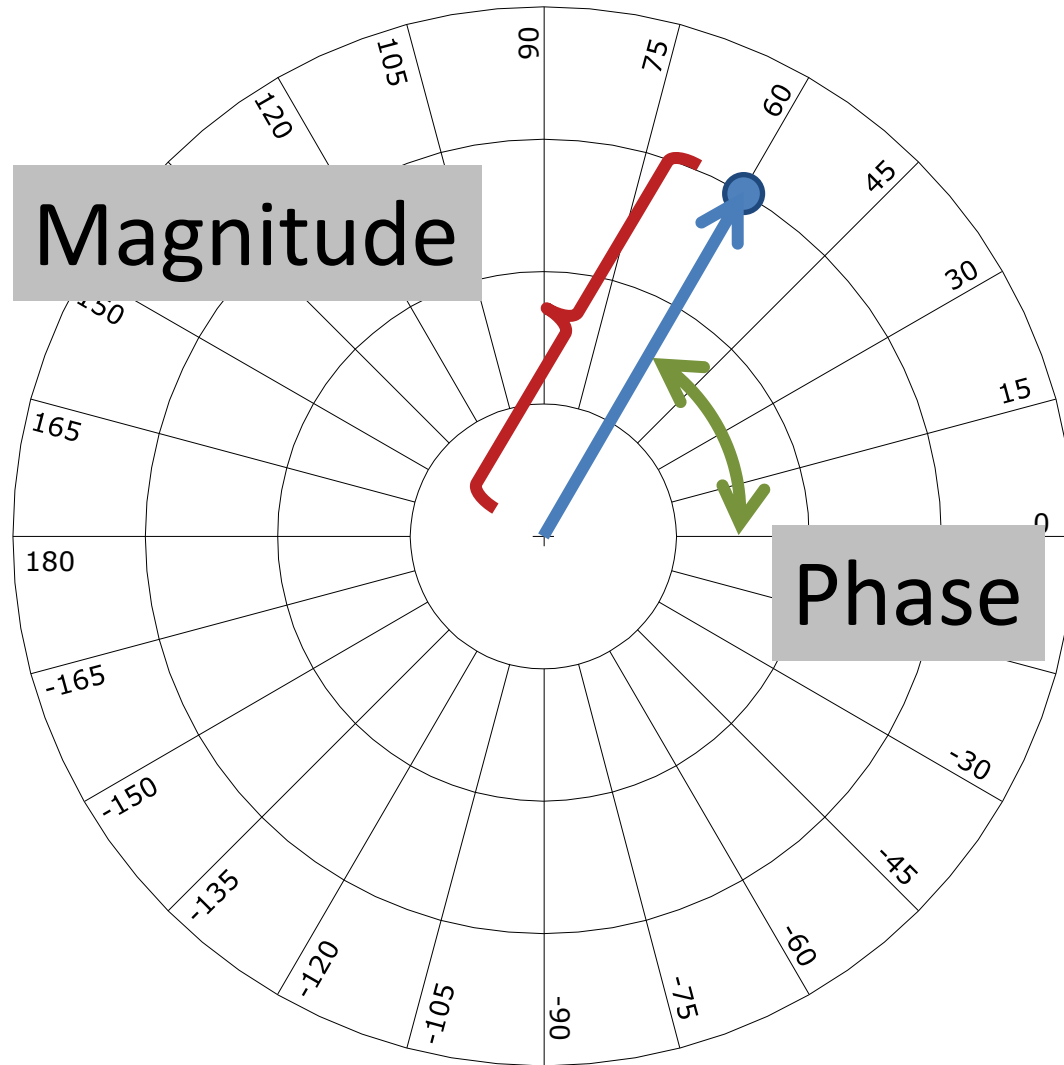


Why “Vector” ?

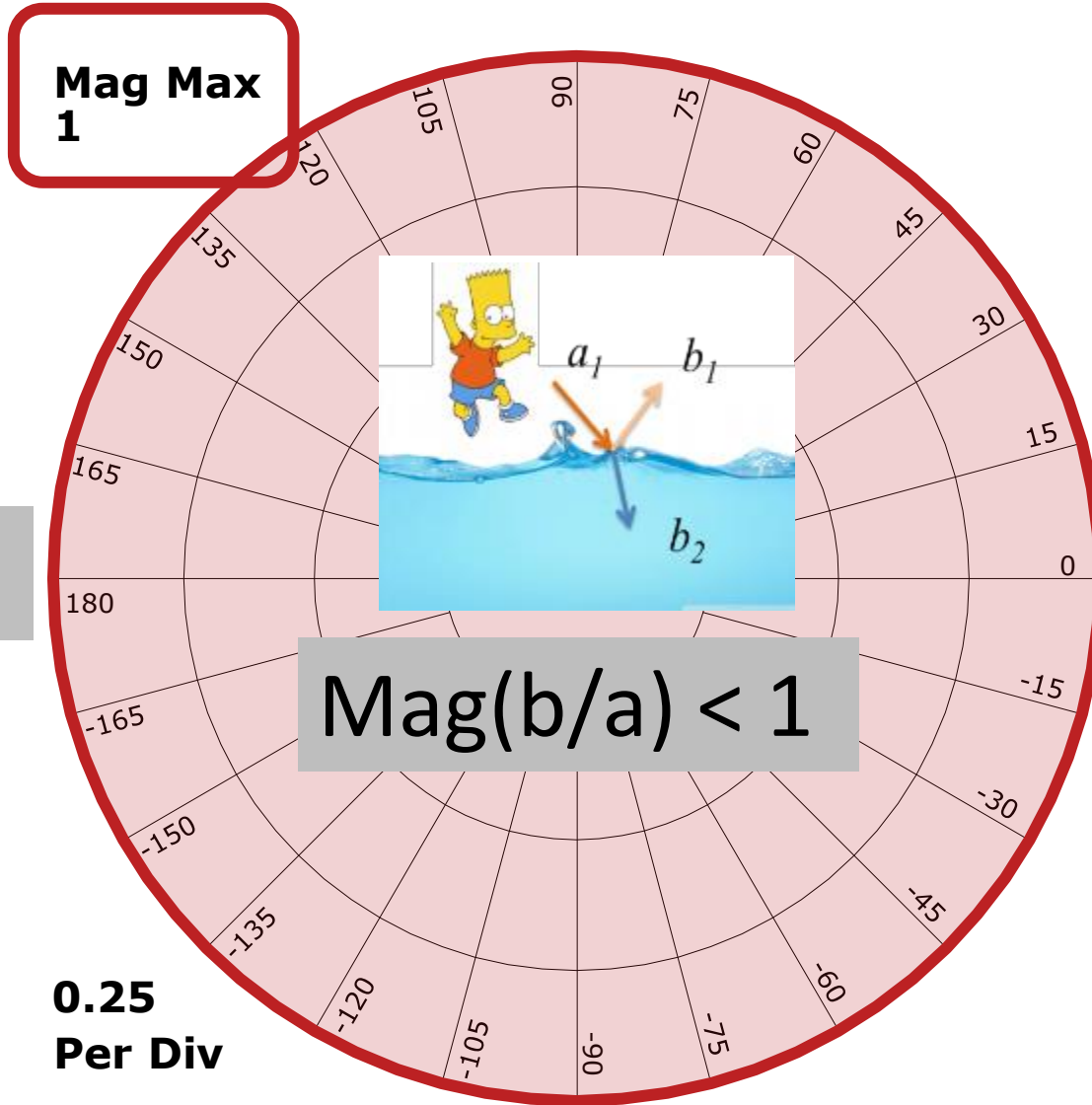
- S-parameters are complex quantities:
 - Magnitude
 - Phase



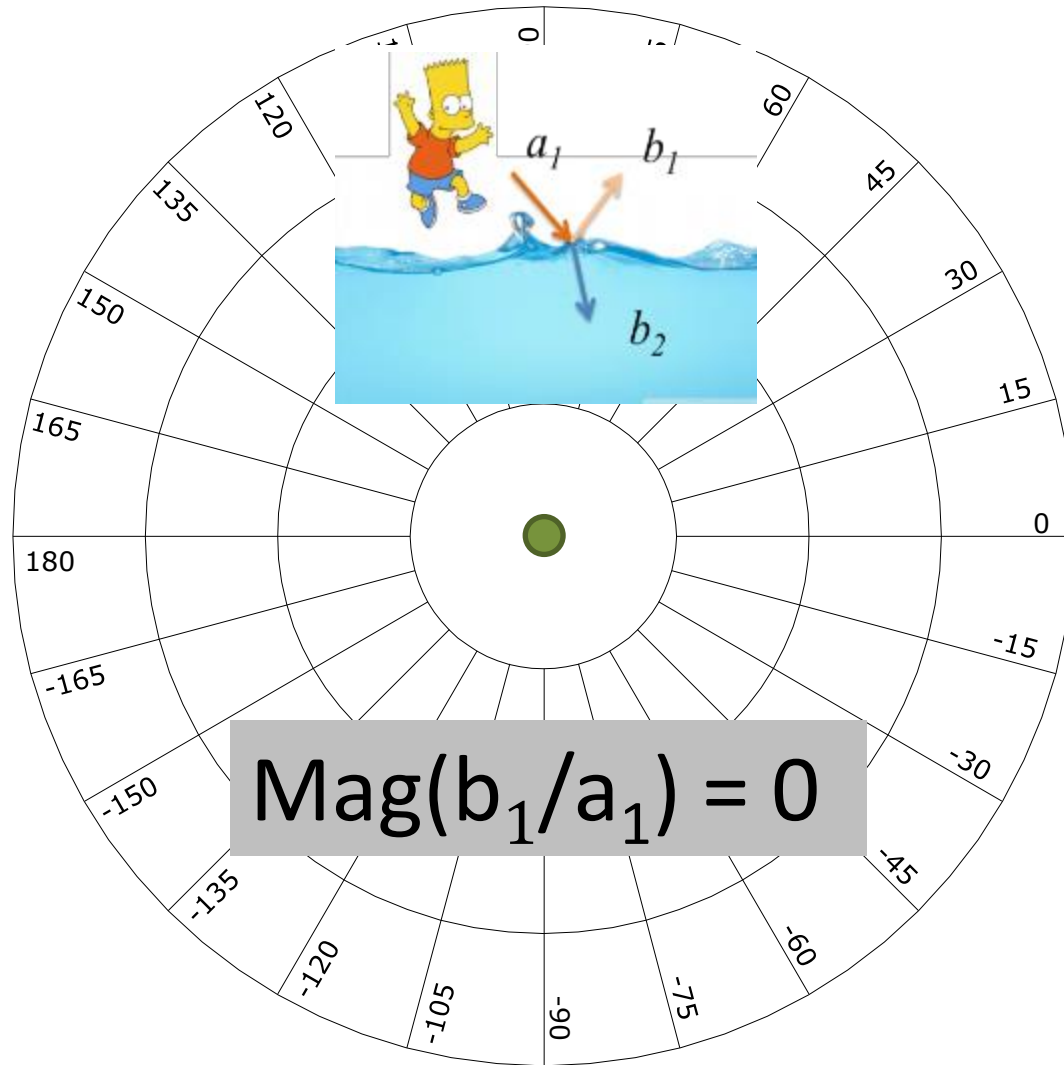
Vector on Polar Plot



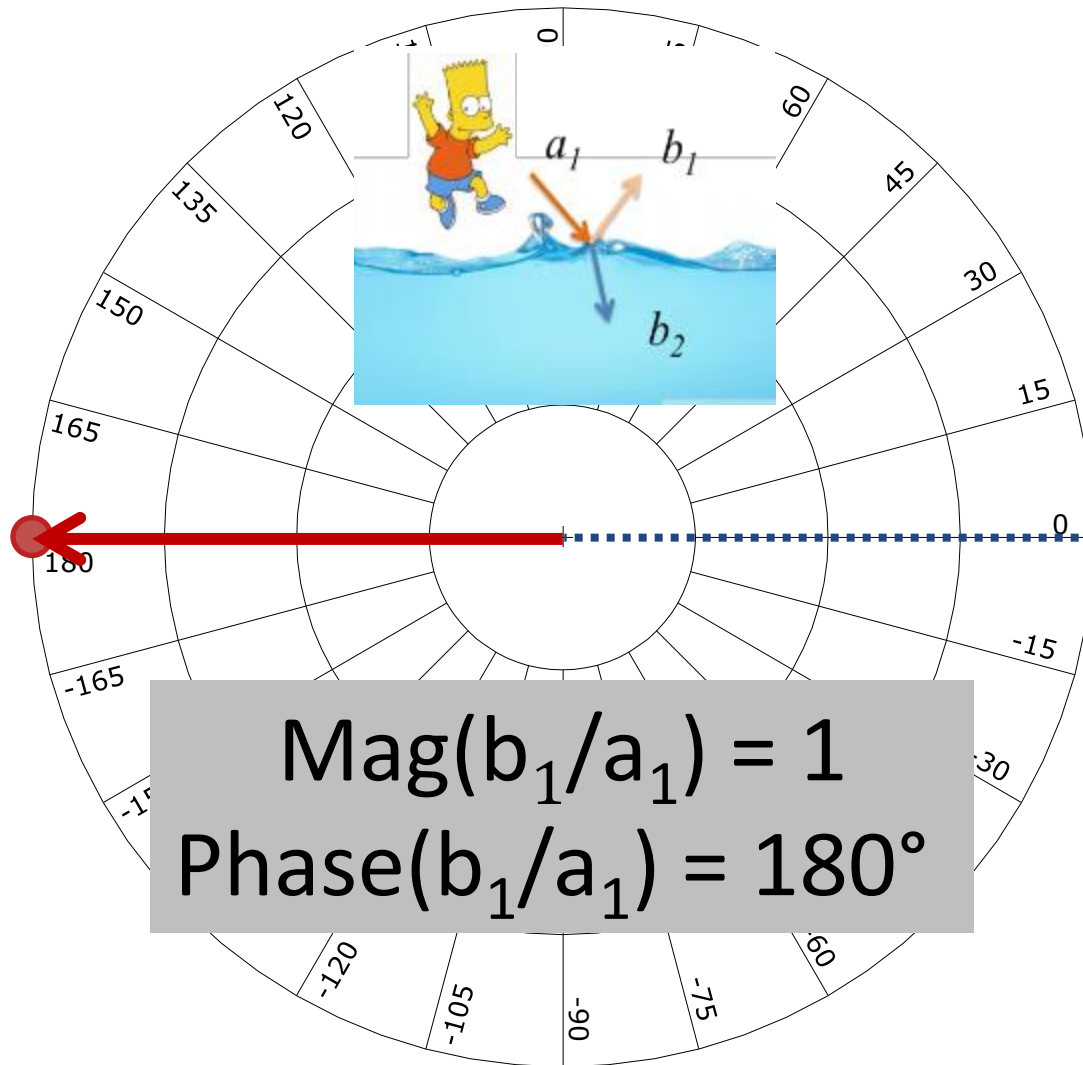
Passive Component



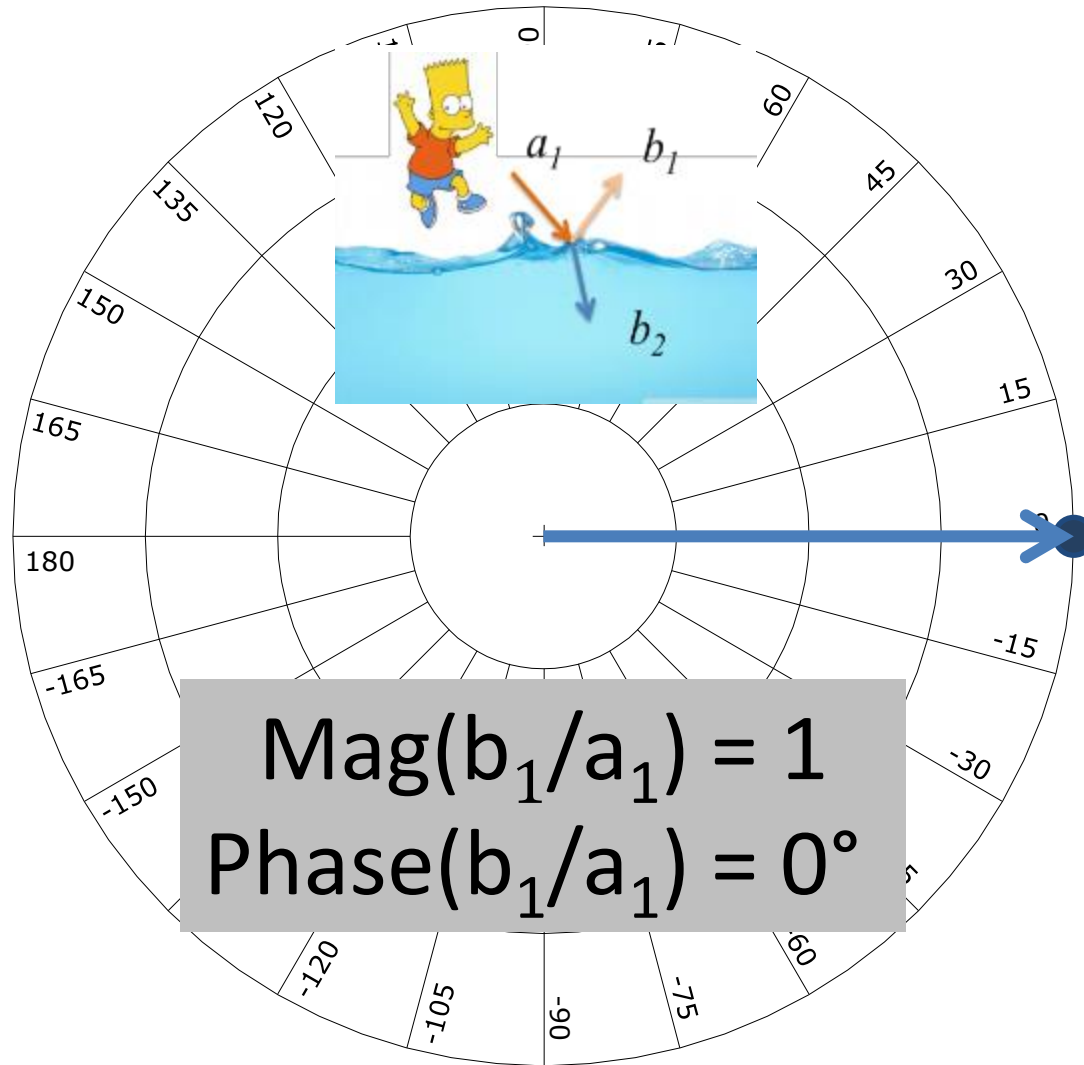
Match (Load)



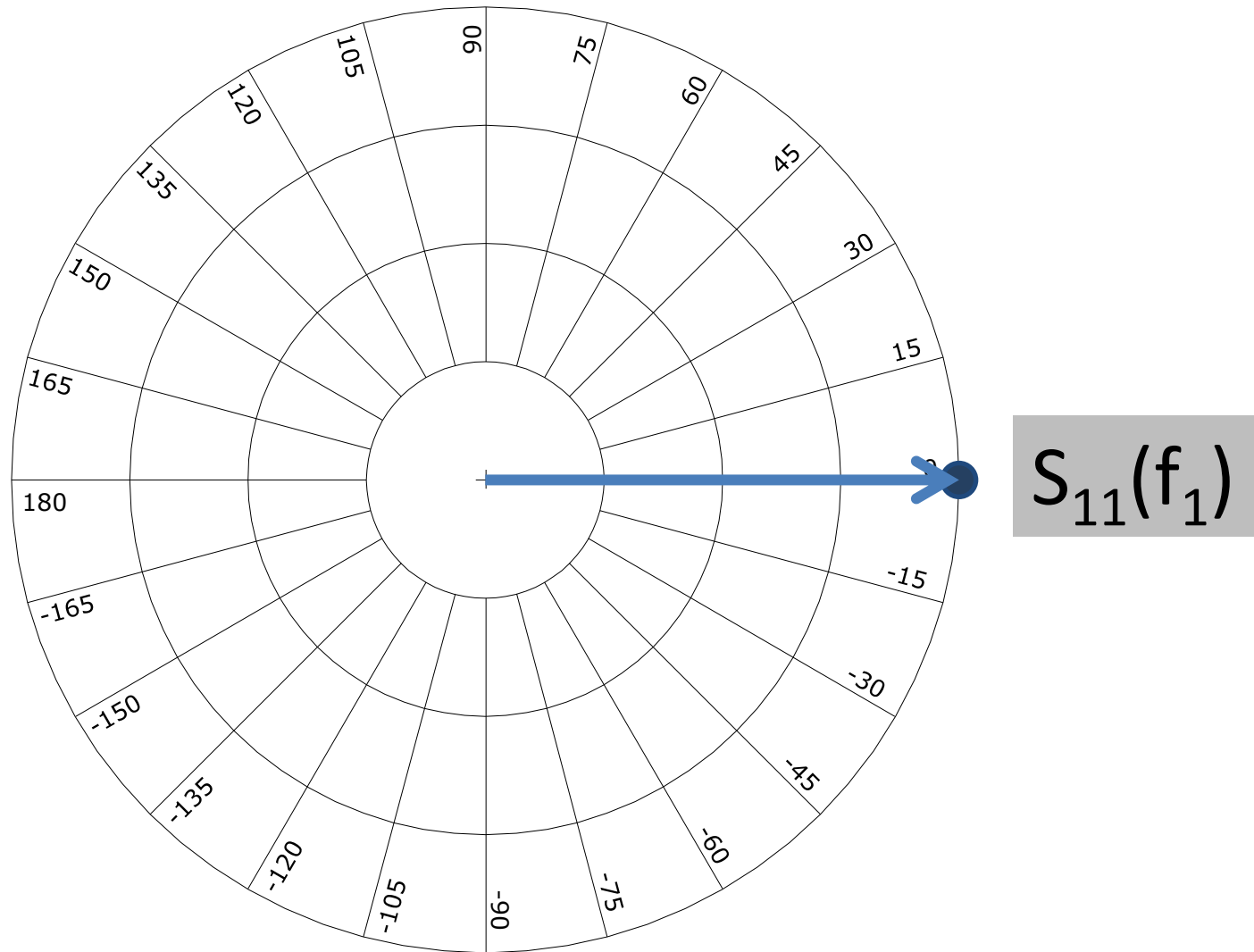
Short



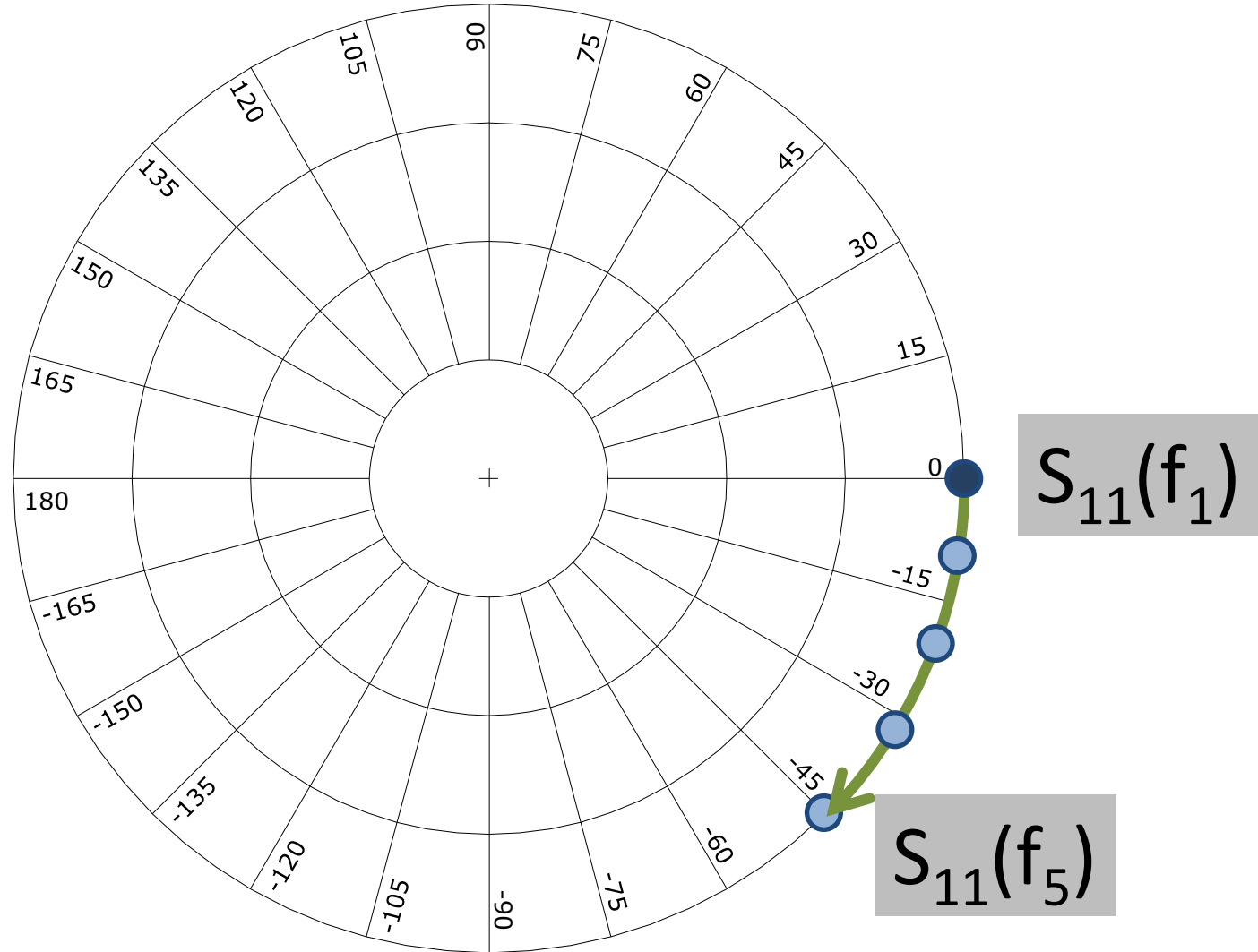
Open



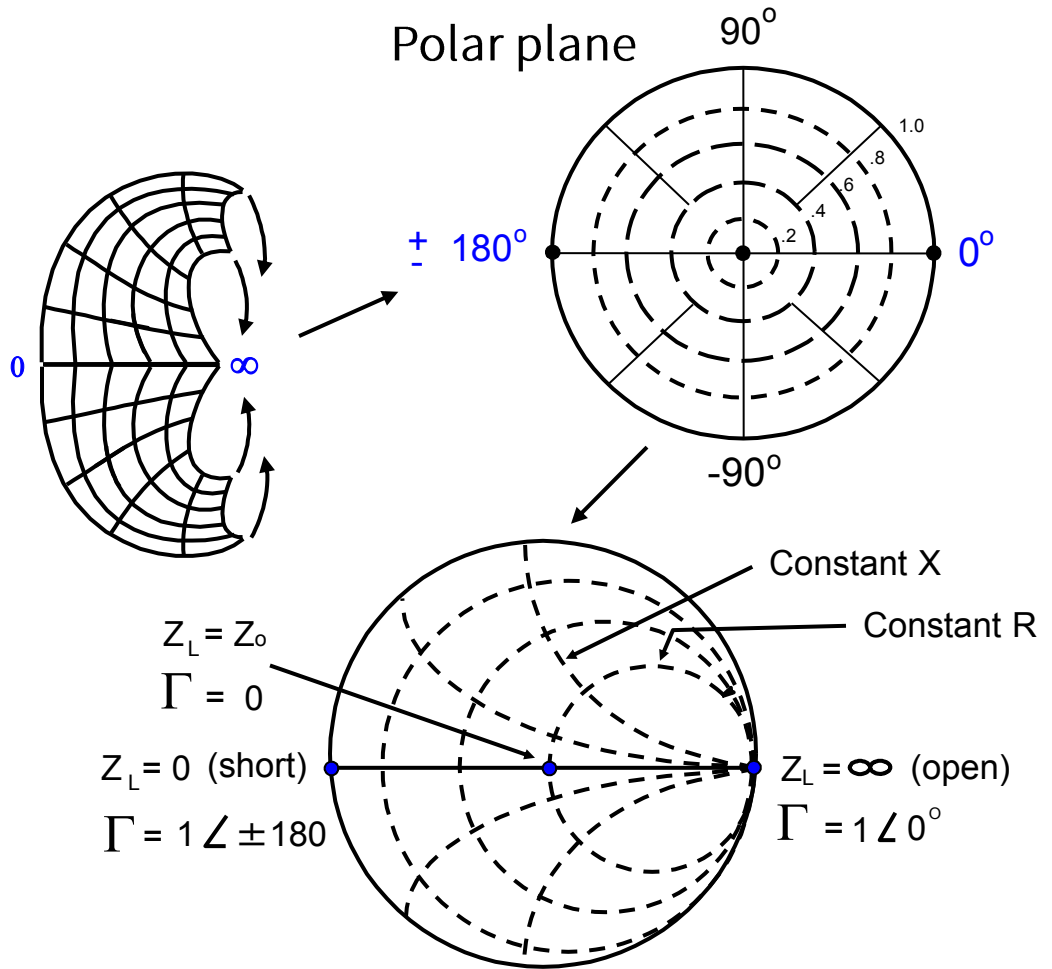
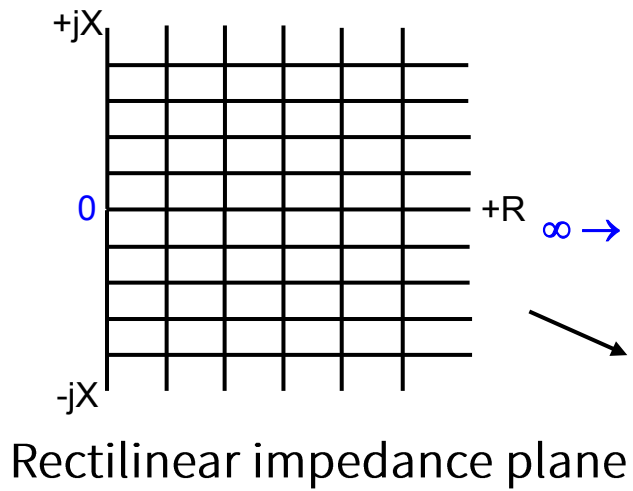
Data over Frequency



Data over Frequency

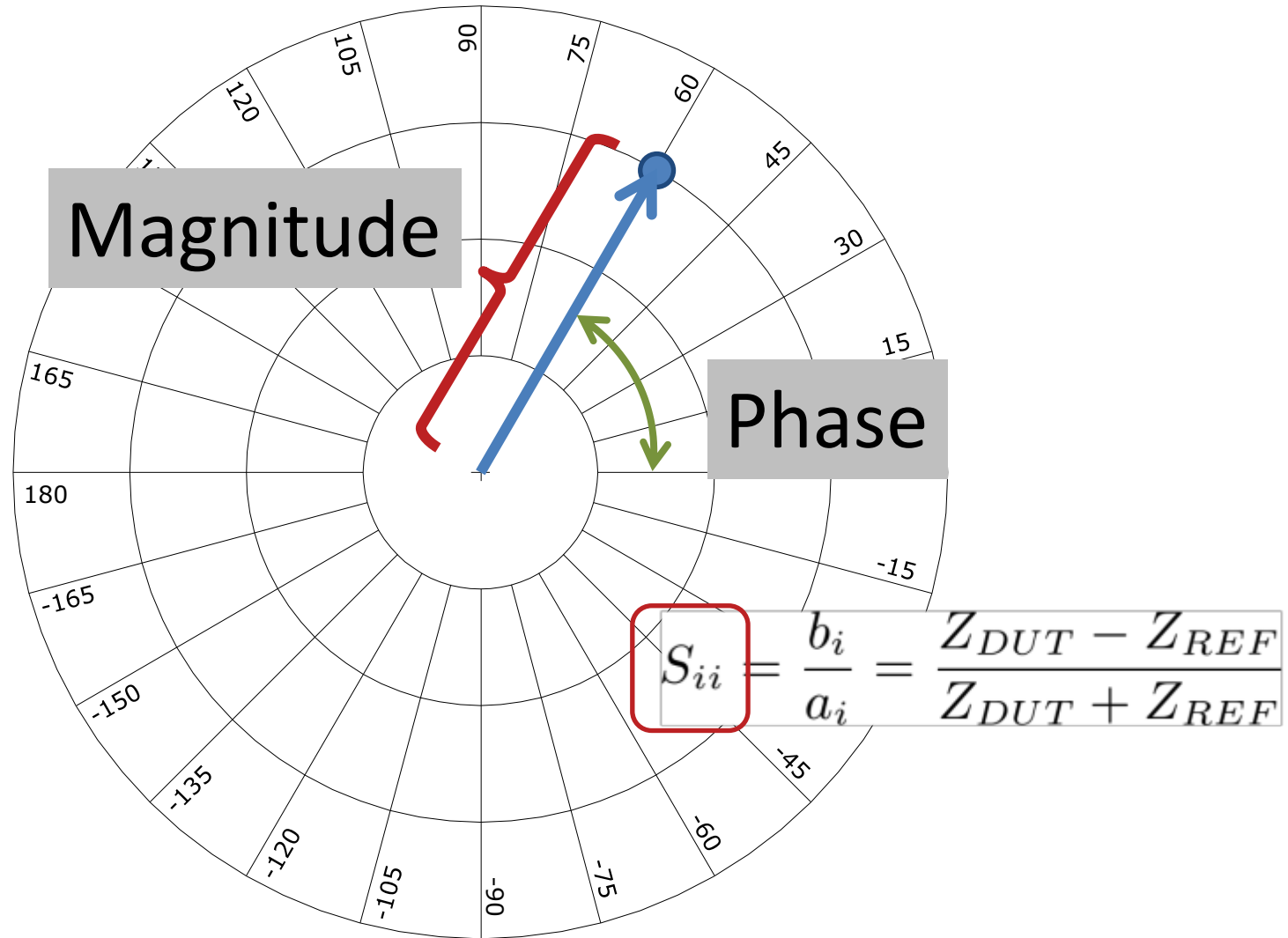


Smith Chart

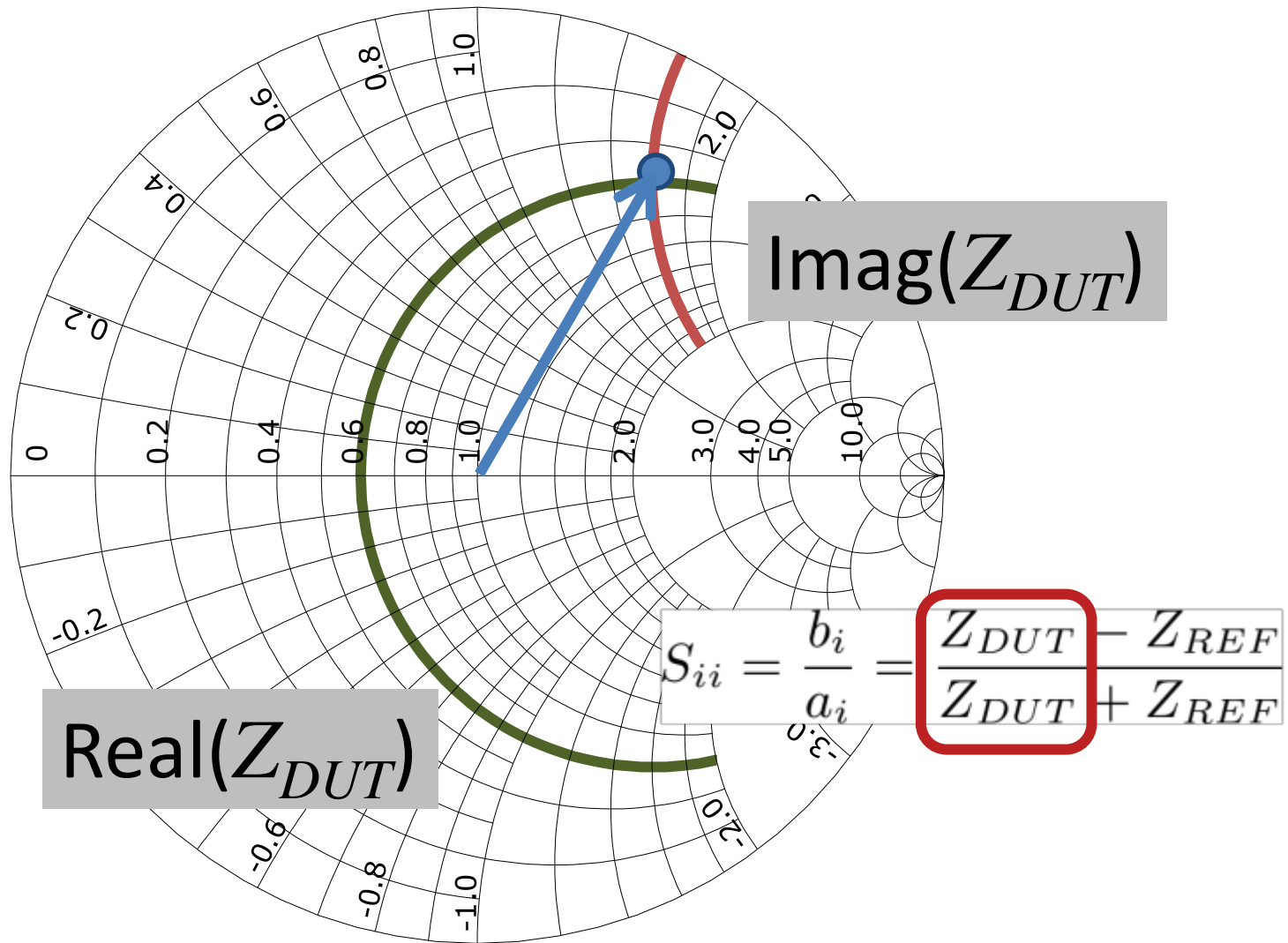


Smith Chart maps
rectilinear impedance
plane onto polar plane

Polar Chart vs. Smith Chart



Polar Chart vs. Smith Chart



Matching of two Media = Transparency

Z_0 (AIR)



Z_0 (WATER)

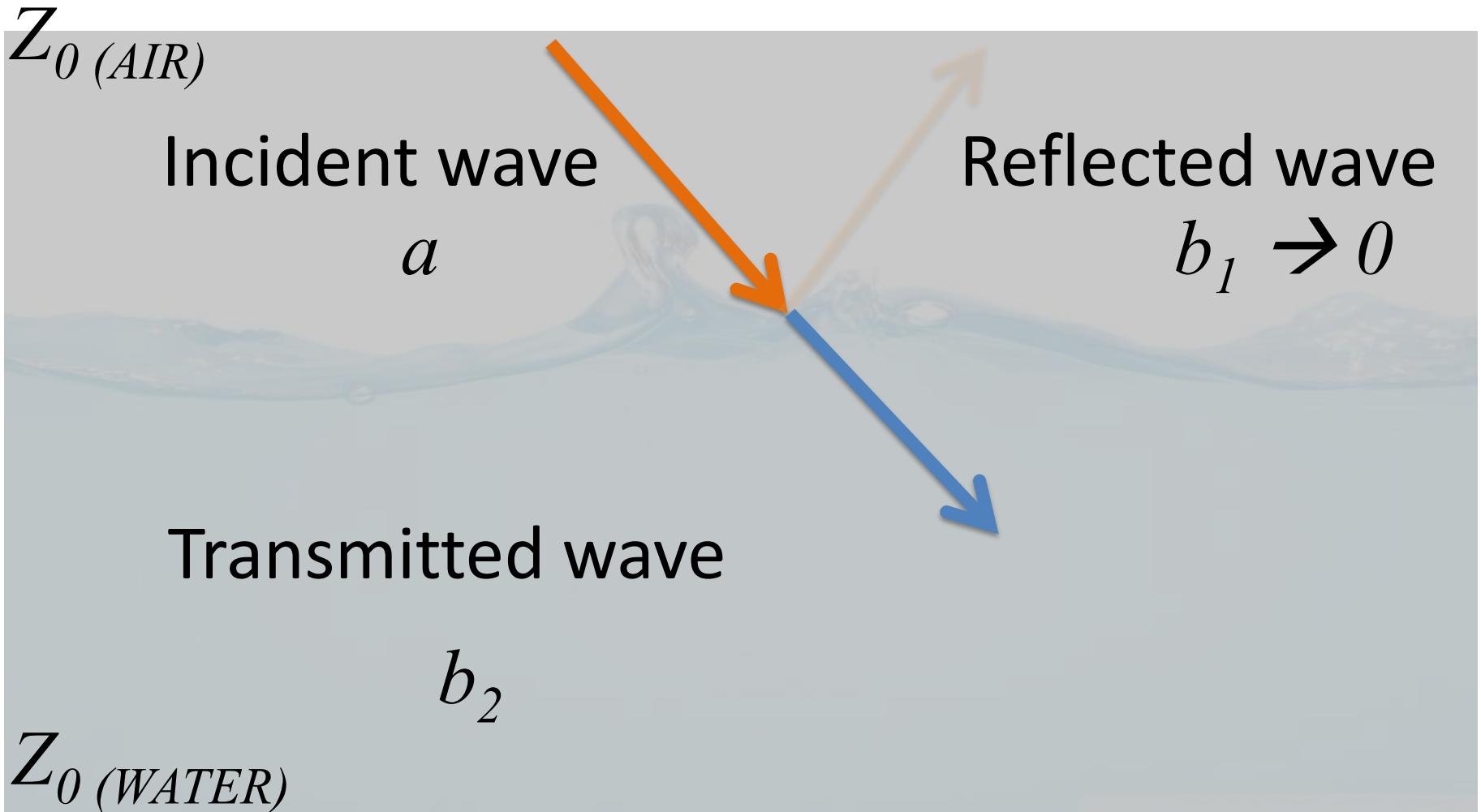
Matching of two Media = Transparency

Z_0 (AIR)



Z_0 (WATER)

Matching of two Media = Transparency



Matching Conditions

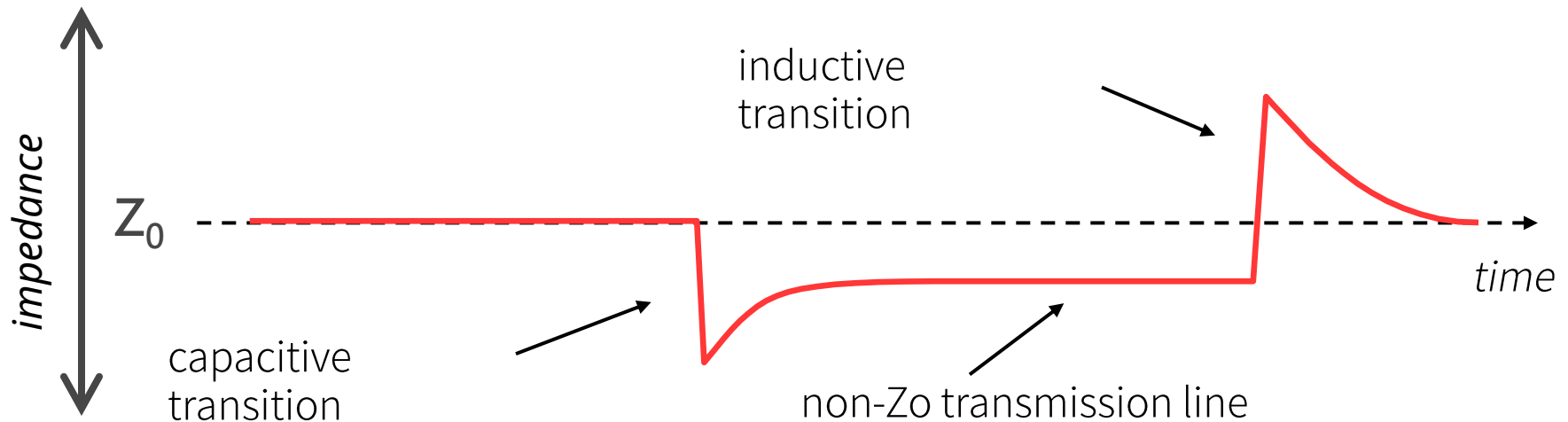
$$S_{ii} = \frac{b_i}{a_i} = \frac{Z_{DUT} - Z_{REF}}{Z_{DUT} + Z_{REF}}$$

$$b_i \rightarrow 0 \quad Z_{DUT} = Z_{REF} \quad S_{ii} \rightarrow 0$$

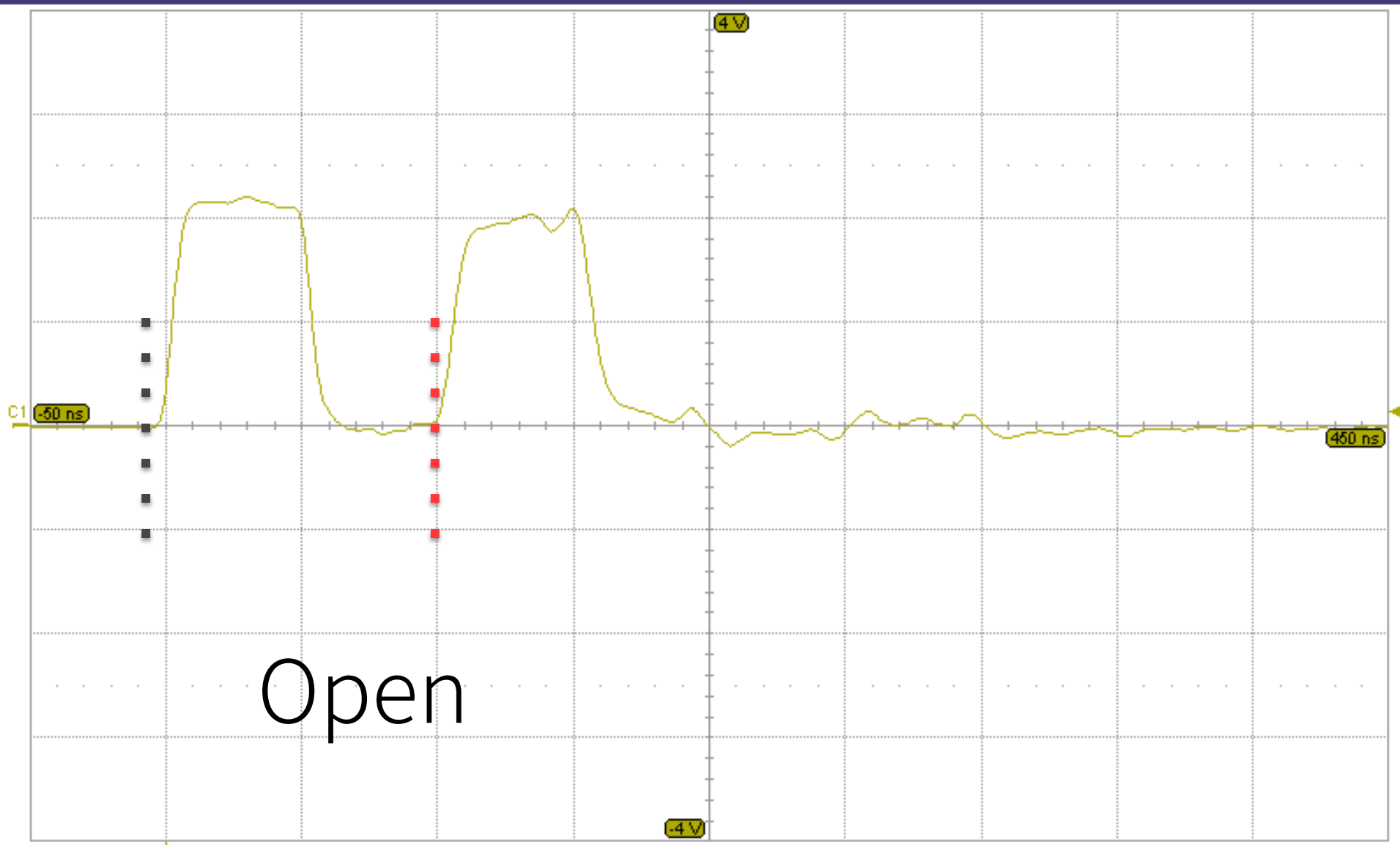
$$Z_{REF} = 50 \, \Omega$$

Time-Domain Reflectometry (TDR)

- Analyze impedance versus time
- Distinguish between inductive and capacitive transitions



Picture source: D. Ballo Keysight



C1 [A] [F] [DC1M]
1.00 V/div
0.0 mV ofst
29.809 k#

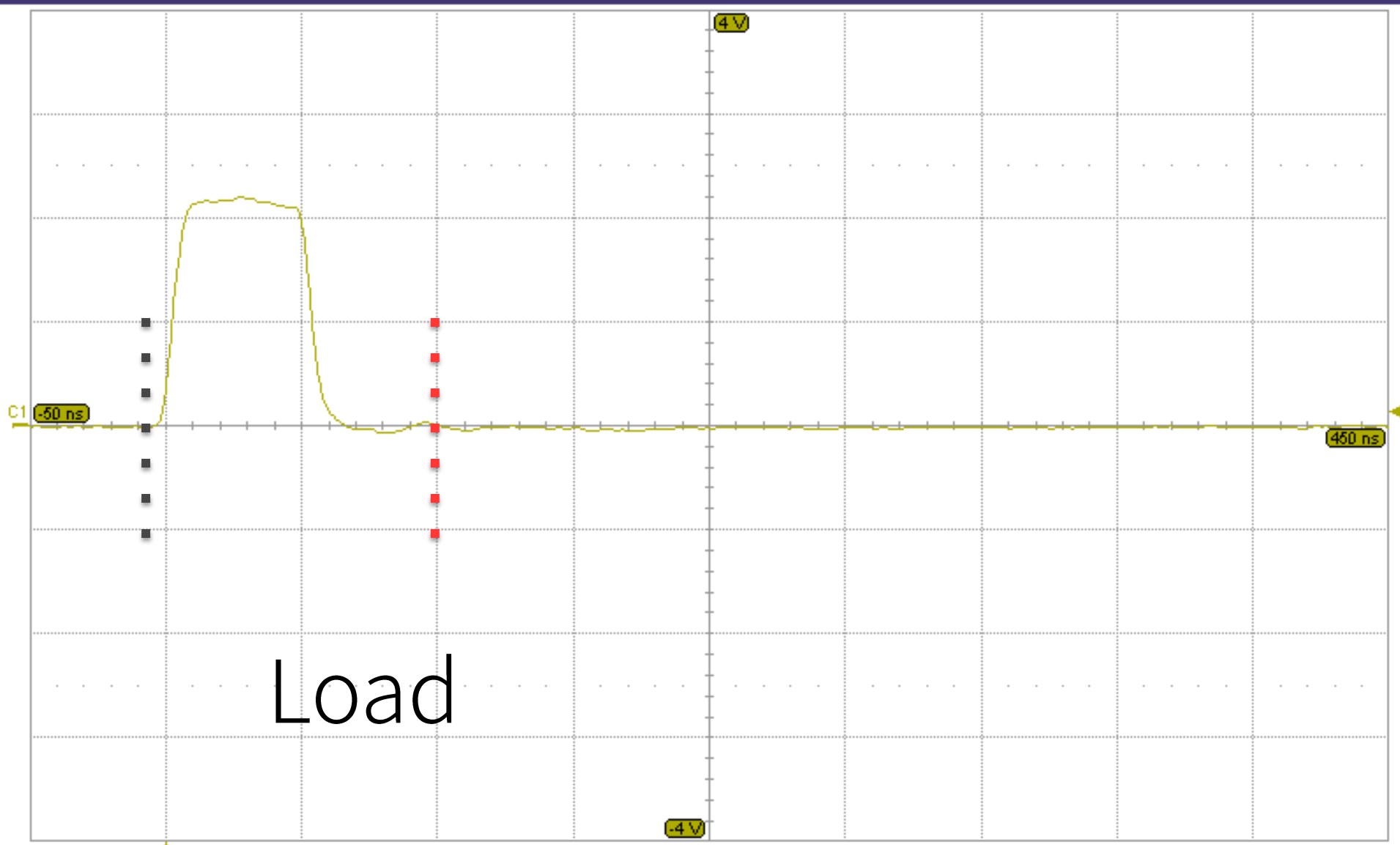
Timebase	-200 ns	Trigger	C1
	50.0 ns/div	Stop	130 mV
500 S	1.0 GS/s	Edge	Positive



Short

C1 **A F DC1M**
1.00 V/div
0.0 mV ofst
30.460 k#

Timebase	-200 ns	Trigger	C1
	50.0 ns/div	Stop	130 mV
500 S	1.0 GS/s	Edge	Positive



Load

C1 **A F DC1M**
1.00 V/div
0.0 mV ofst
30.916 k#

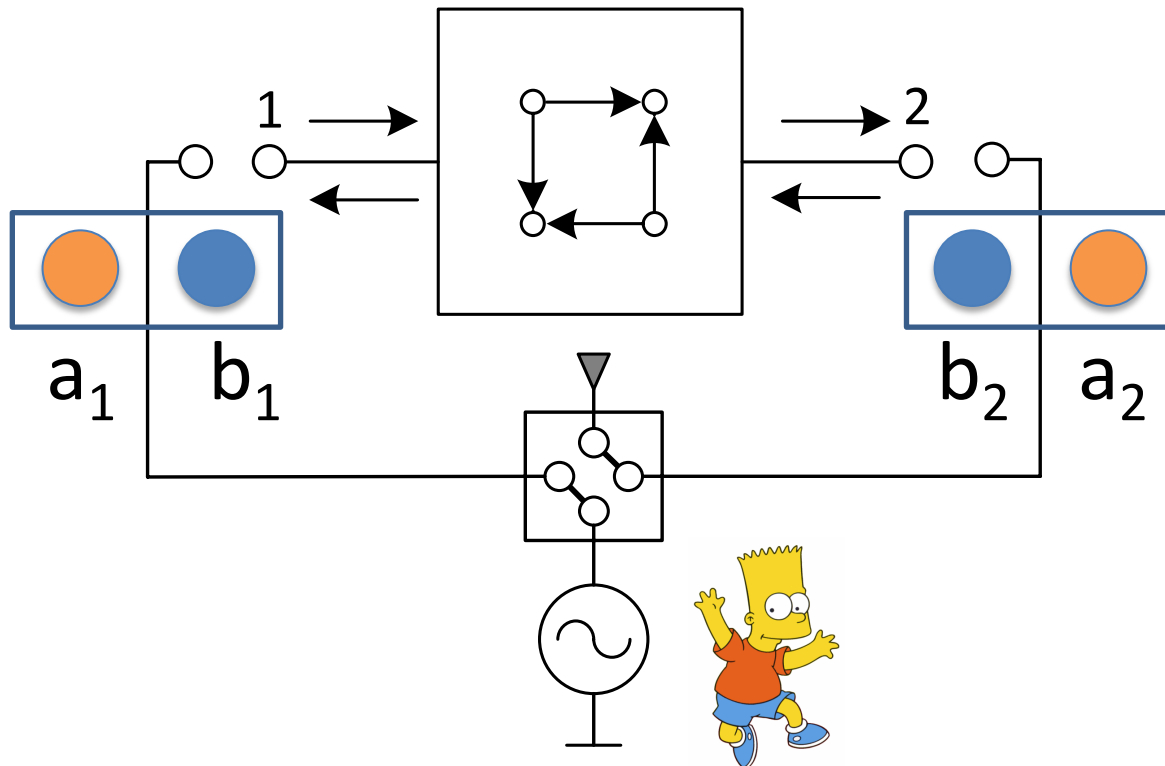
Timebase	-200 ns	Trigger	C1
	50.0 ns/div	Stop	130 mV
500 S	1.0 GS/s	Edge	Positive

Outline

- Introduction
- S-parameters Basics
- Measurement of S-parameters
- VNA Building Blocks
- Instrumentation

Vector Network Analyzer

Device Under Test (DUT)



At the early days...



- Dr. Rohde and Dr. Schwarz first commercial product for RF measurement: 1933
- Z-g Graph from Rohde & Schwarz, early 50s

End of 60s...70s...80s...



HP 8410



Wiltron 310

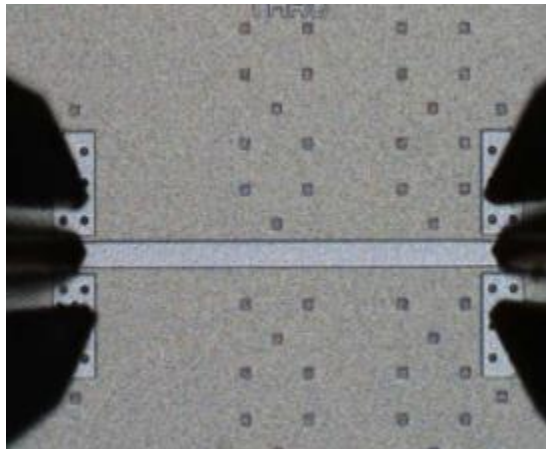
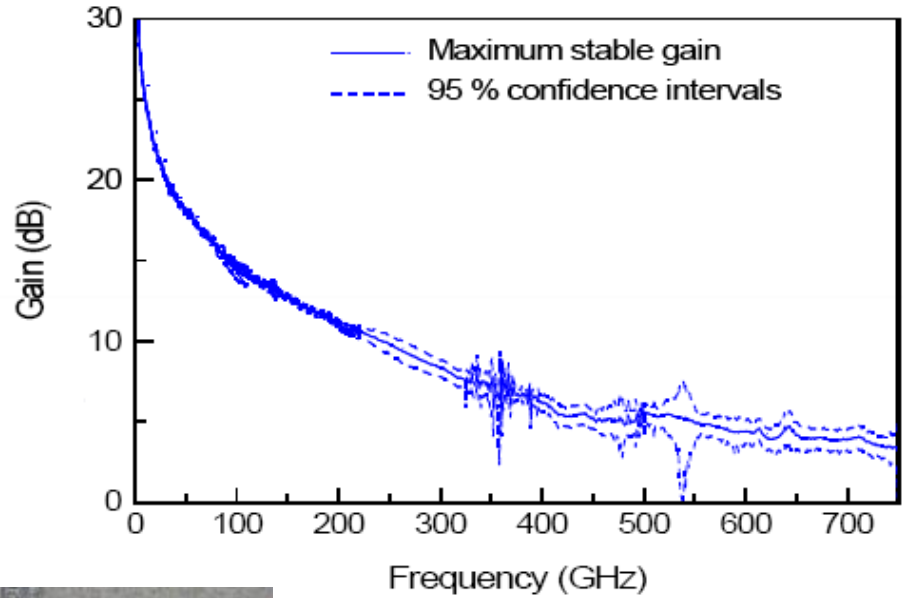
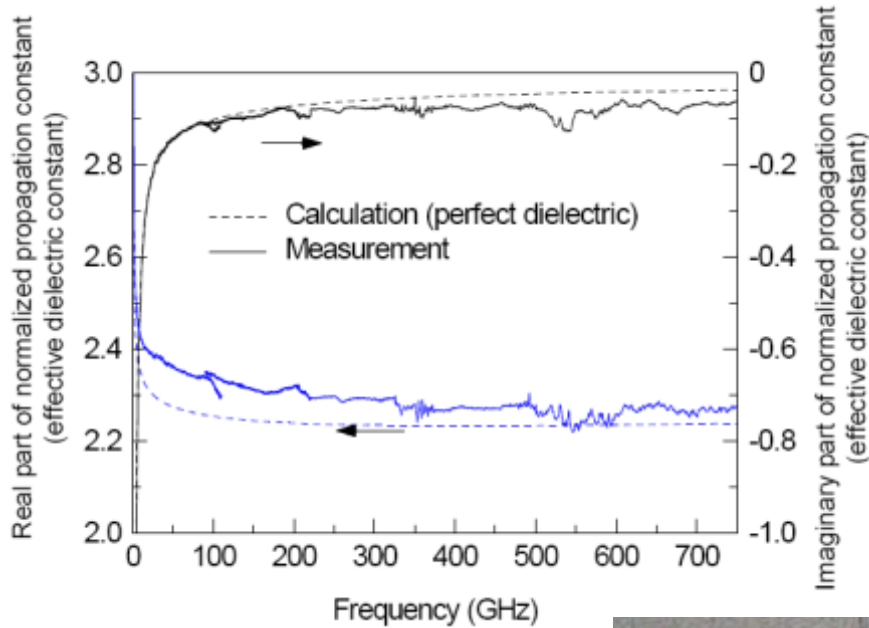


R&S

HP8410 Still Alive!



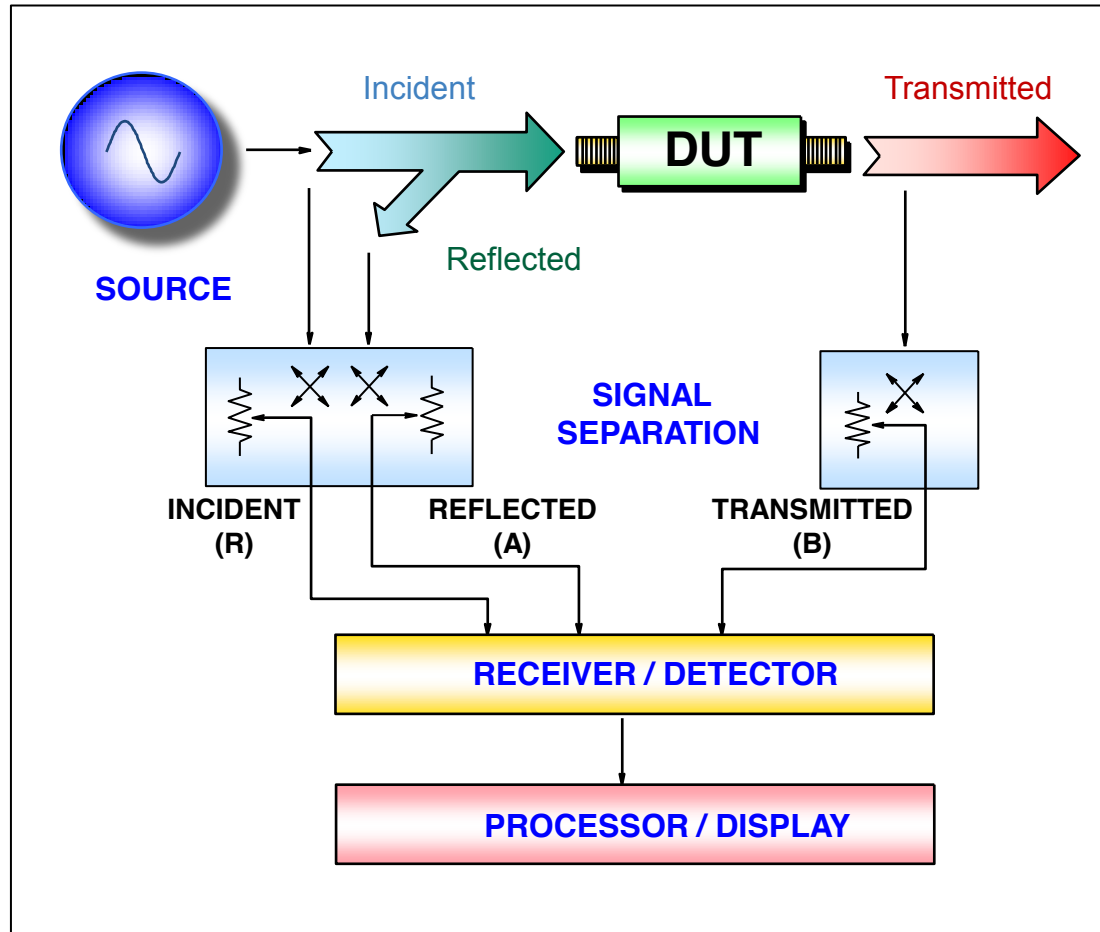
Today: On-Wafer Measurement



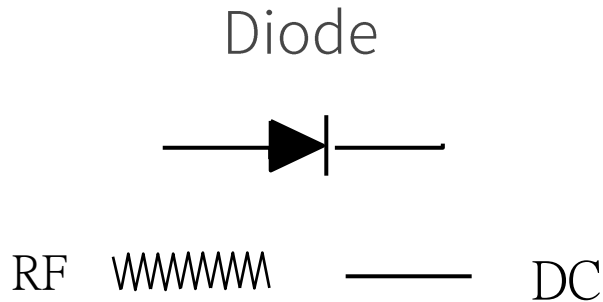
Outline

- Introduction
- S-parameters Basics
- Measurement of S-parameters
- VNA Building Blocks
- Instrumentation

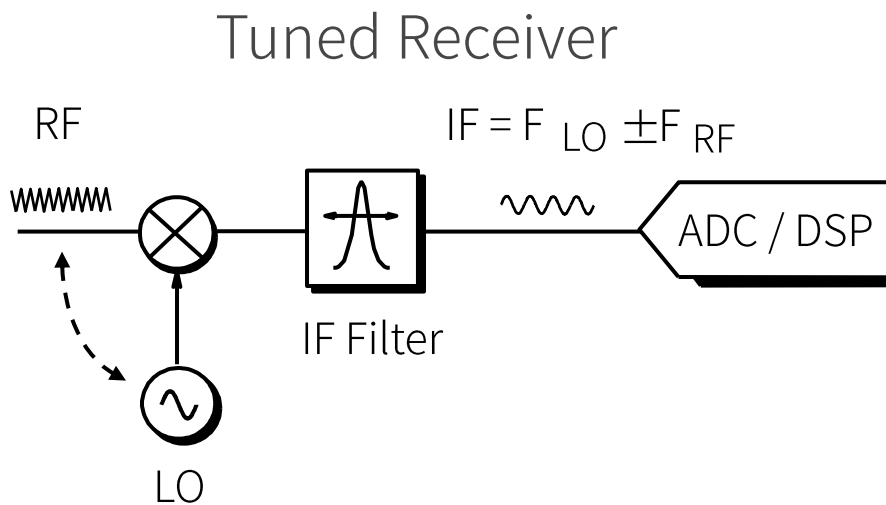
VNA Building Blocks



Receiver / Detectors

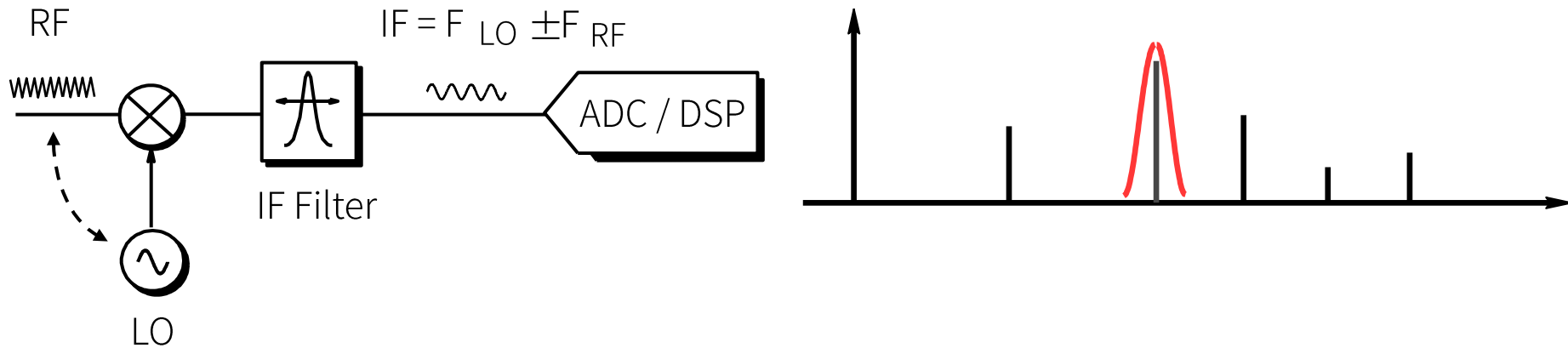


Scalar
(no phase information)



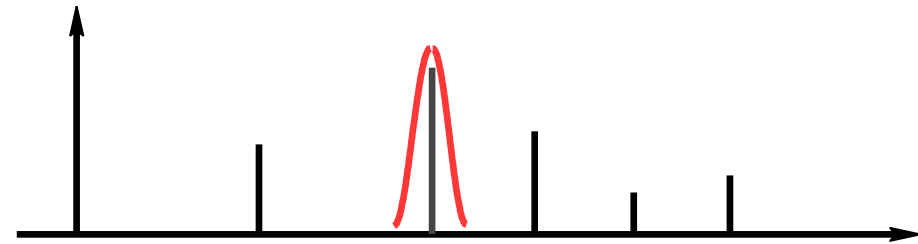
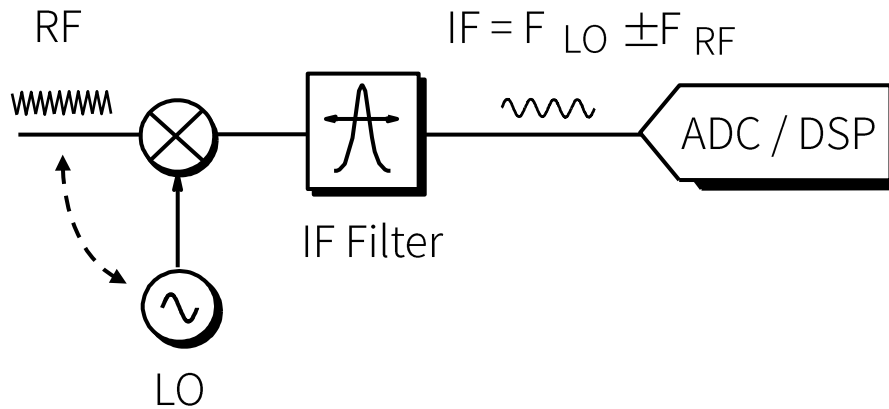
Vector
(magnitude and phase)

Narrowband Detection: Heterodyne Receiver



- Best sensitivity / dynamic range
- Provides harmonic / spurious signal rejection

Narrowband Detection: Heterodyne Receiver

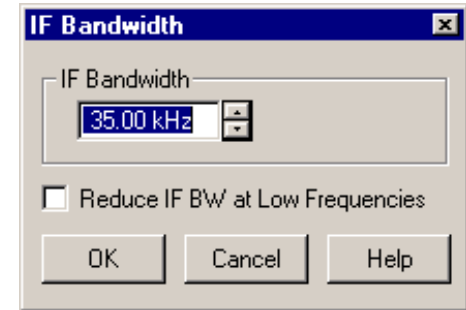


Trade off: noise floor and measurement speed

IF Bandwidth and Averaging

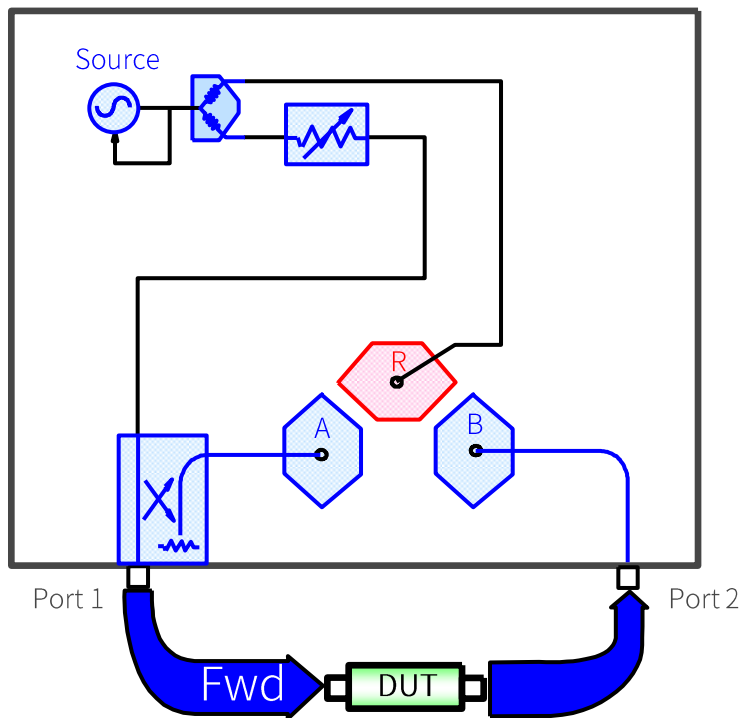
- Improve dynamic range by:
 - increasing power,
 - decreasing IF bandwidth, or
 - Averaging

- Recommended IFBW value 100 Hz
- Averaging : OFF



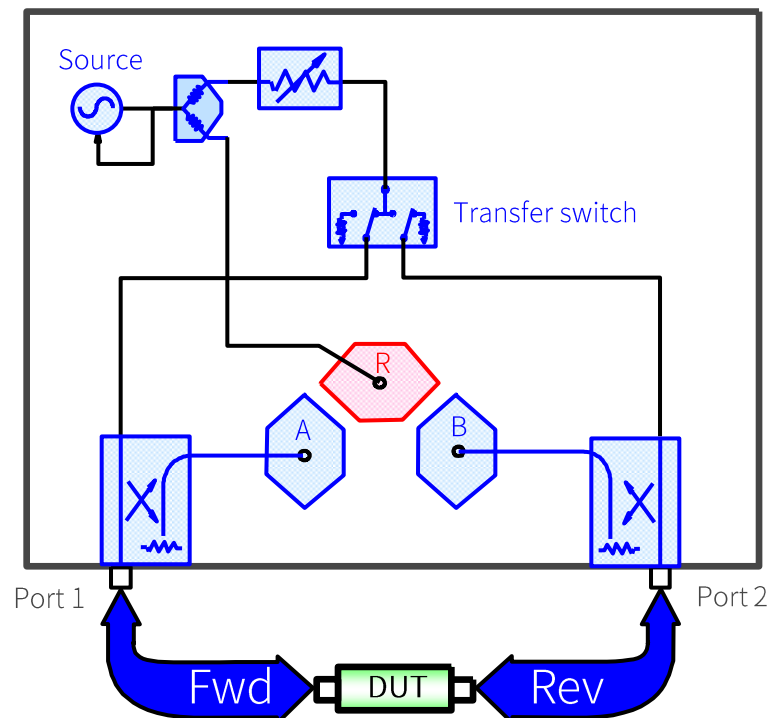
T/R Versus S-Parameter Test Sets

Transmission/Reflection Test Set



RF always comes out port 1
 Port 2 is always receiver
 Response, one-port cal available

S-Parameter Test Set

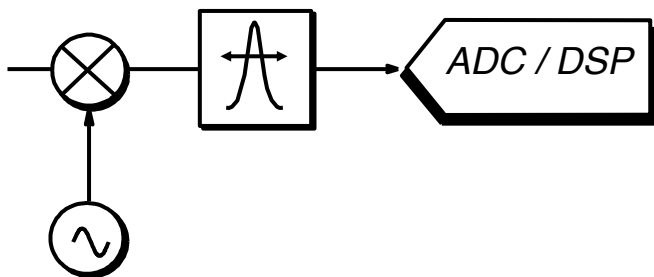


RF comes out port 1 or port 2
 Forward and reverse measurements
 Two-port calibration possible

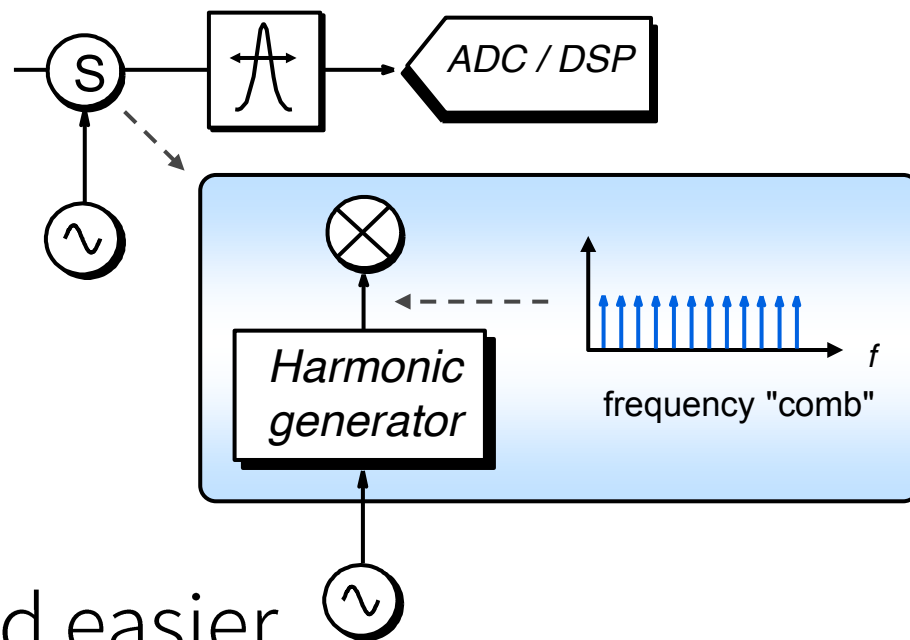
Picture source: D. Ballo Keysight

Front Ends: Mixers Versus Samplers

Mixer-based front end

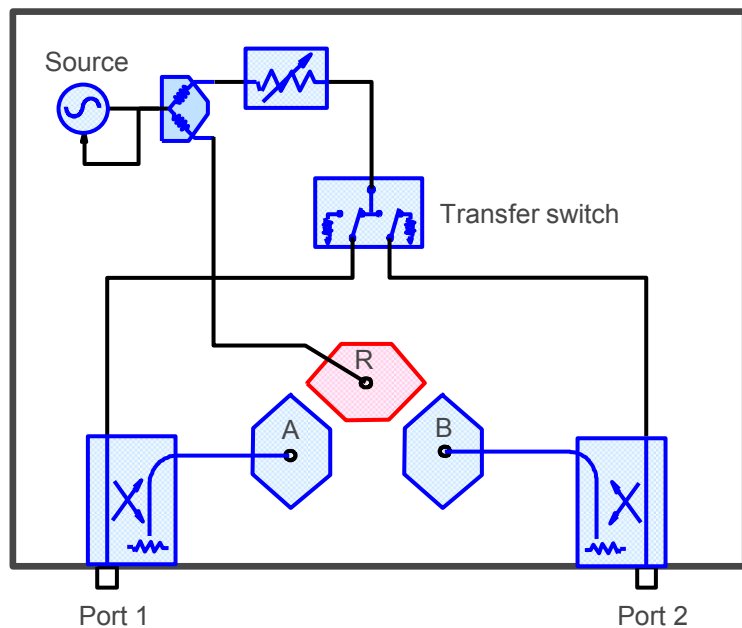


Sampler-based front end

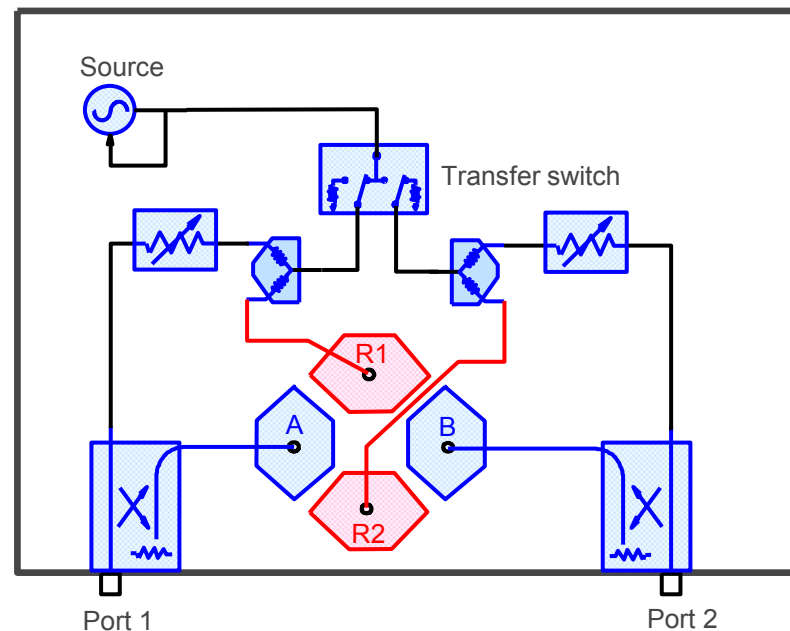


- Samplers: cheaper and easier
- Dynamic range?

Three vs. Four-Receiver Analyzers



- Reference Channel
 - Economy
 - Up to 20 GHz



- Double-Reflectometer
 - High-end
 - Up to THz

Picture source: D. Ballo Keysight

Outline

- Introduction
- S-parameters Basics
- Measurement of S-parameters
- VNA Building Blocks
- Instrumentation

What do we have today?

Instruments

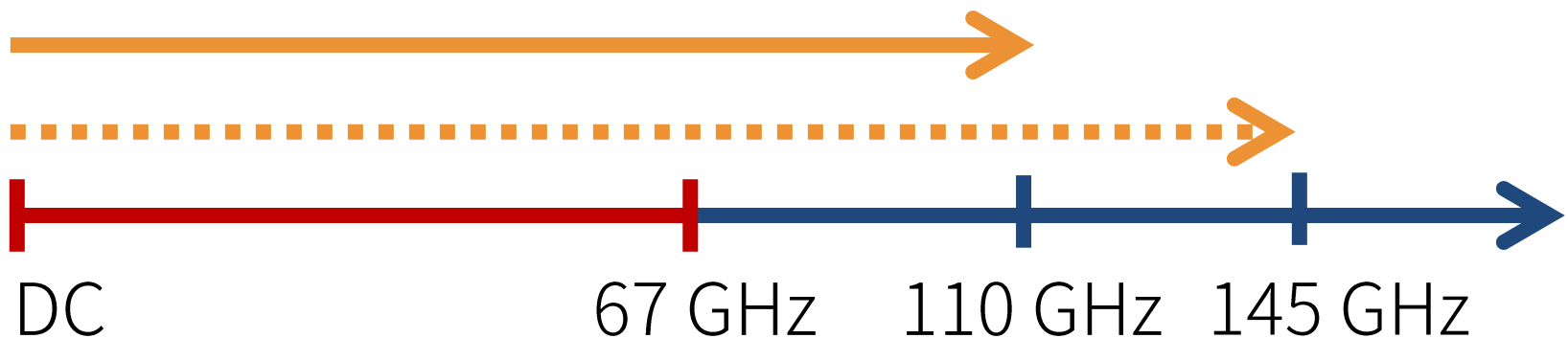


Frequency Extenders

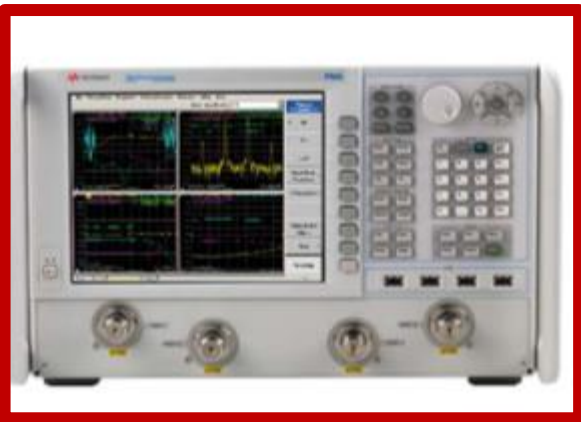


Frequency Range

- Baseband unit
 - From few Hz to 67 GHz
- Frequency extenders
 - From 67 GHz to 1.1 THz
 - Single sweep: from DC to 110 GHz (145 GHz)



Keysight (former Agilent)



PNA-X



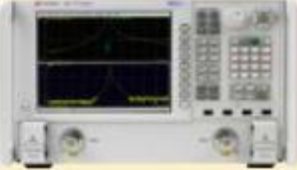


FiledFox PXI-VNA







ENA

PNA Family

	Model	Typical application	Frequency range
PNA Family <i>Reach for unrivaled excellence</i>	 <p>N524xA PNA-X Series <i>Most advanced and flexible VNA</i></p>	<ul style="list-style-type: none"> – Replace an entire rack of equipment with one instrument – Complete linear and nonlinear active device characterization 	<ul style="list-style-type: none"> – 10 MHz to 8.5/13.5/26.5/43.5/50/67 GHz – Up to 1.1 THz with extenders
	 <p>N522xA PNA Series <i>High performance microwave VNA</i></p>	<ul style="list-style-type: none"> – Highest performance passive component analysis – Active components characterization – Metrology and cal lab 	<ul style="list-style-type: none"> – 10 MHz to 13.5/26.5/43.5/50/67 GHz – Up to 1.1 THz with extenders
	 <p>N523xA PNA-L Series <i>Economy microwave VNA</i></p>	<ul style="list-style-type: none"> – Microwave S-parameter test – Signal integrity – Material measurements 	<ul style="list-style-type: none"> – 300 kHz to 8.5/13.5/20 GHz – 10 MHz to 43.5/50 GHz

ENA Family

ENA
Drive down
the cost
of test

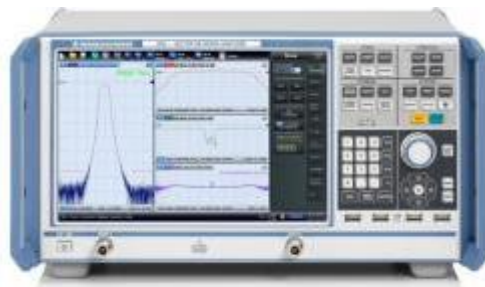
Model	Typical application	Frequency range
 <p>E5072A ENA <i>High performance RF VNA with configurable test set</i></p>	<ul style="list-style-type: none"> – RF amplifier test – BTS components – PIM measurements 	<ul style="list-style-type: none"> – 30 kHz to 4.5/8.5 GHz
 <p>E5071C ENA <i>High performance RF VNA</i></p>	<ul style="list-style-type: none"> – RF component test – Multiport module test – Material measurements – Signal integrity 	<ul style="list-style-type: none"> – 9 kHz to 4.5/6.5/8.5 GHz – 300 kHz to 14/20 GHz
 <p>E5061B ENA <i>LF-RF VNA with impedance analysis function</i> <i>Low cost RF VNA</i></p>	<ul style="list-style-type: none"> – LF component/circuit test – Component Z evaluation – RF component test – CATV component test 	<ul style="list-style-type: none"> – 5 Hz to 3 GHz – 100 kHz to 1.5/3 GHz
 <p>E5063A ENA <i>Low-cost RF VNA for passive component test</i></p>	<ul style="list-style-type: none"> – Antenna manufacturing test – RF passive component test – Material measurements – PCB manufacturing test 	<ul style="list-style-type: none"> – 100 kHz to 4.5/8.5/18 GHz



High-end: ZVA



Midrange: ZVB 40GHz



Economy: ZVD 8.5GHz



Portable: ZVL 13.5GHz

Anritsu envision:ensure



VectorStar: ME7838



ShockLine: MS46xxx 40GHz

New Players



S5048 4.8GHz



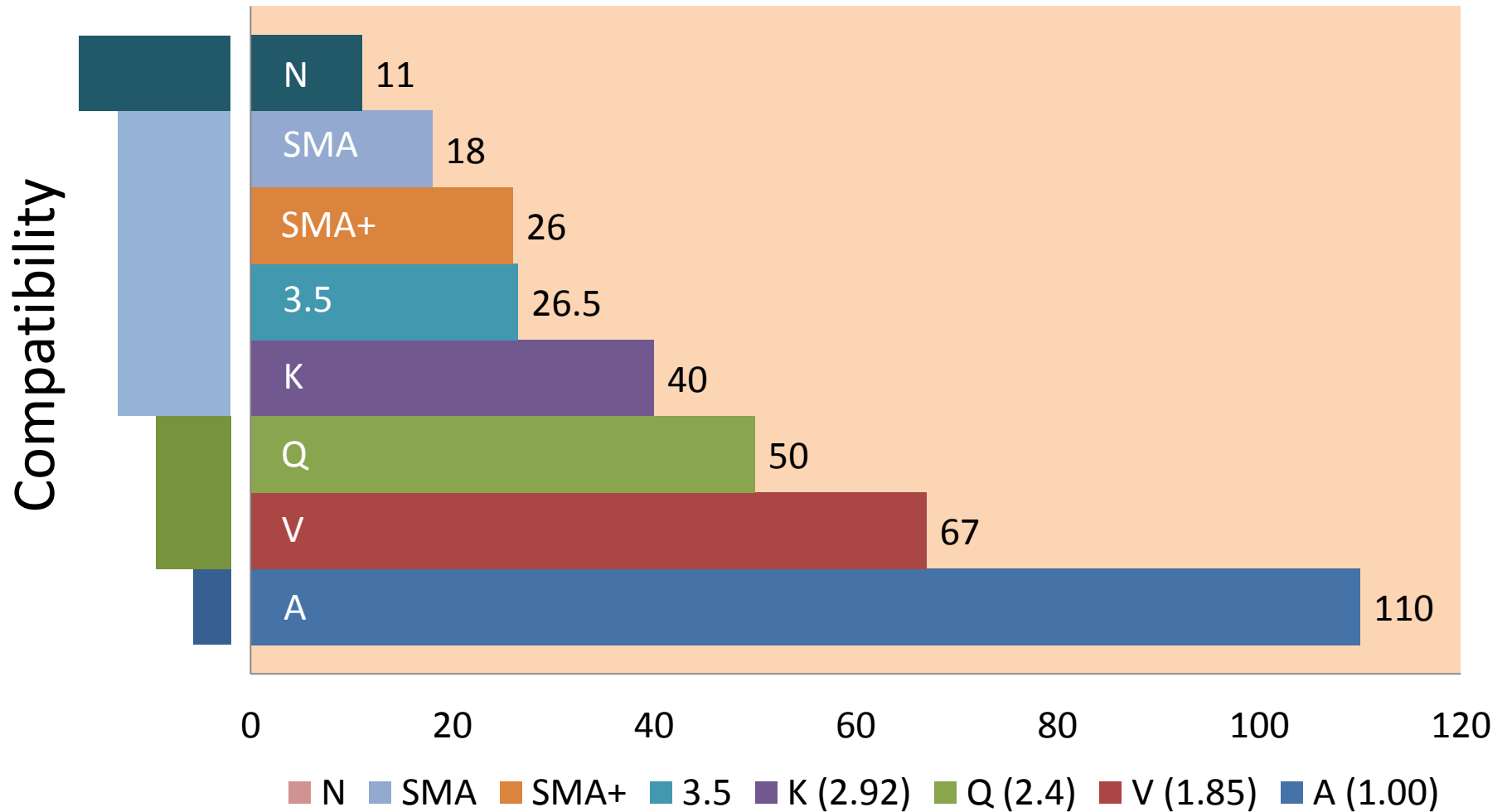
-
-
-

P814 8.0GHz



PXIe-5632. 8.5GHz

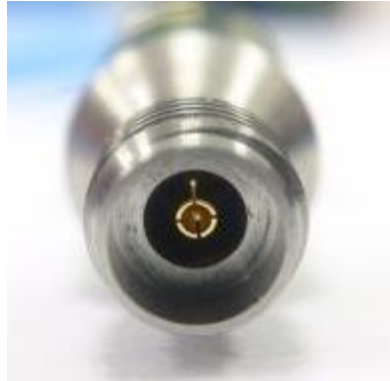
Frequency Limits and Compatibility



Cable and Connectors



SMA



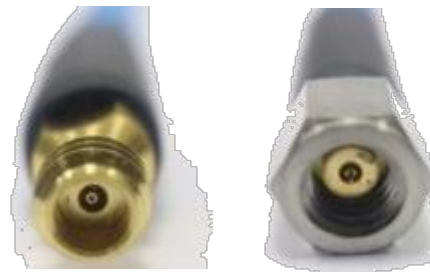
K (2.92 mm)



Q (2.4 mm)



V (1.85 mm)



A (1.00 mm)

Cables



26 GHz



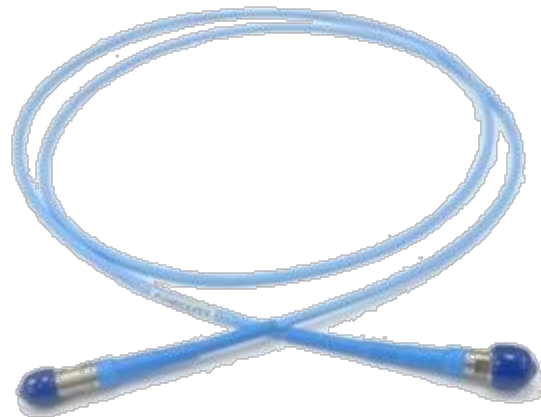
40 GHz



50 GHz



50 GHz

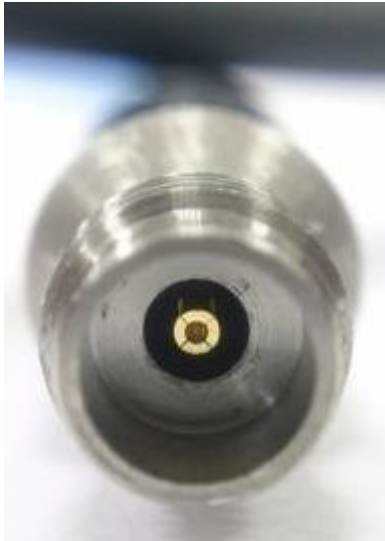


67 GHz

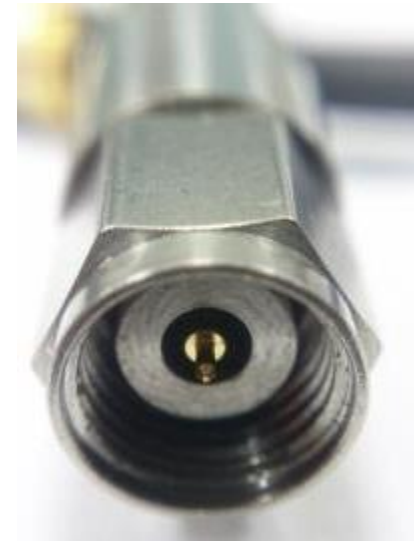


110 GHz

Comparison



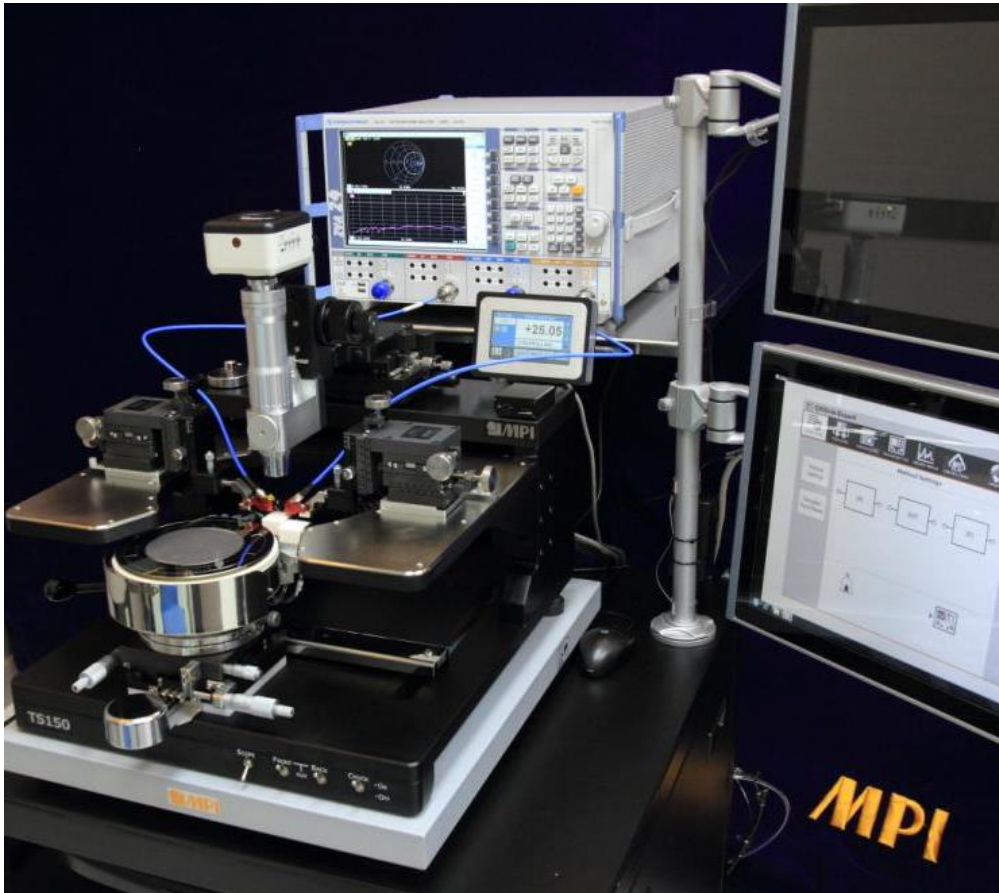
Entry-level



High-end

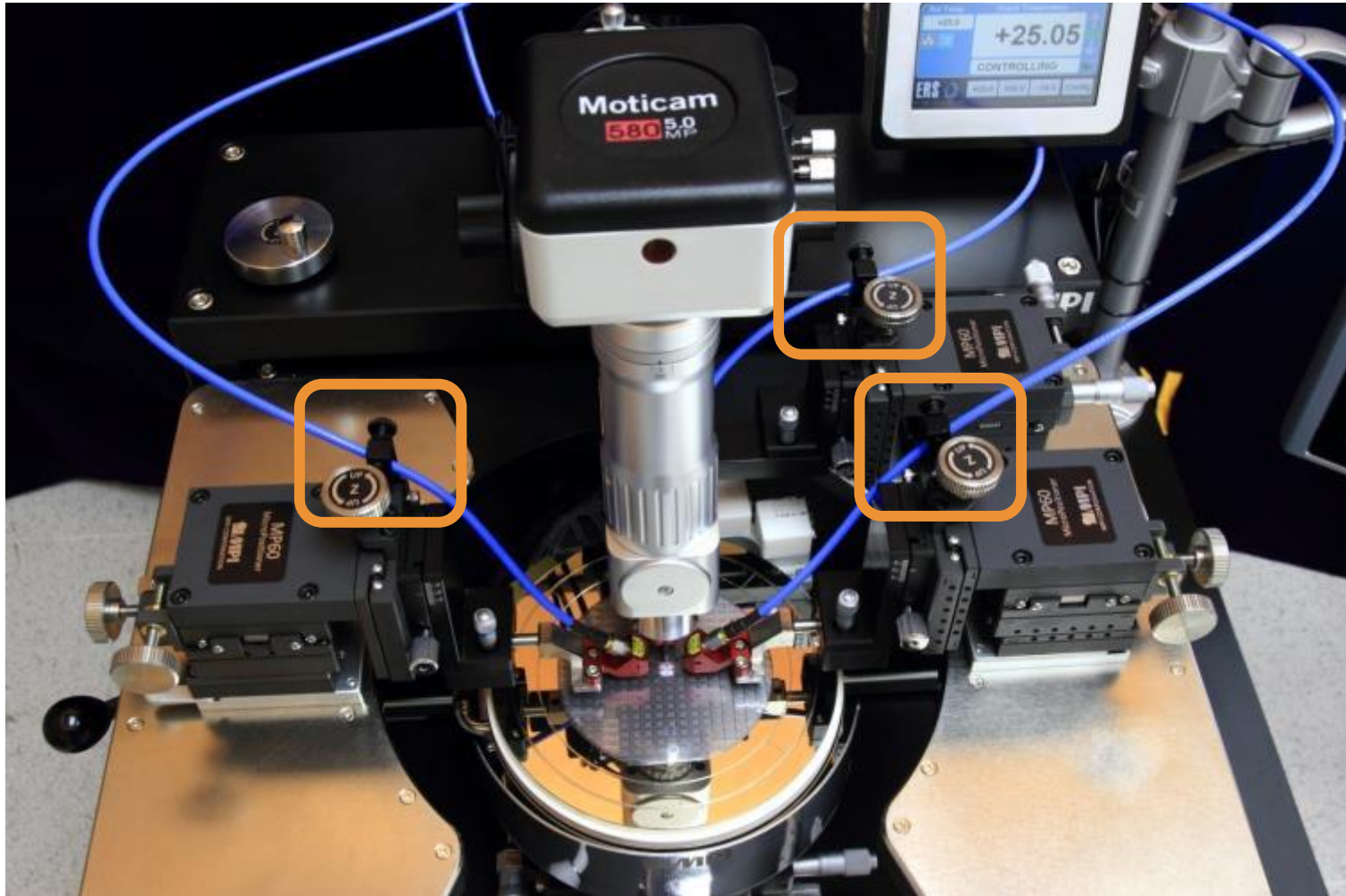


VNA Integration



- At the back
- Integrated shelf
- Optimized cable length: 80 cm

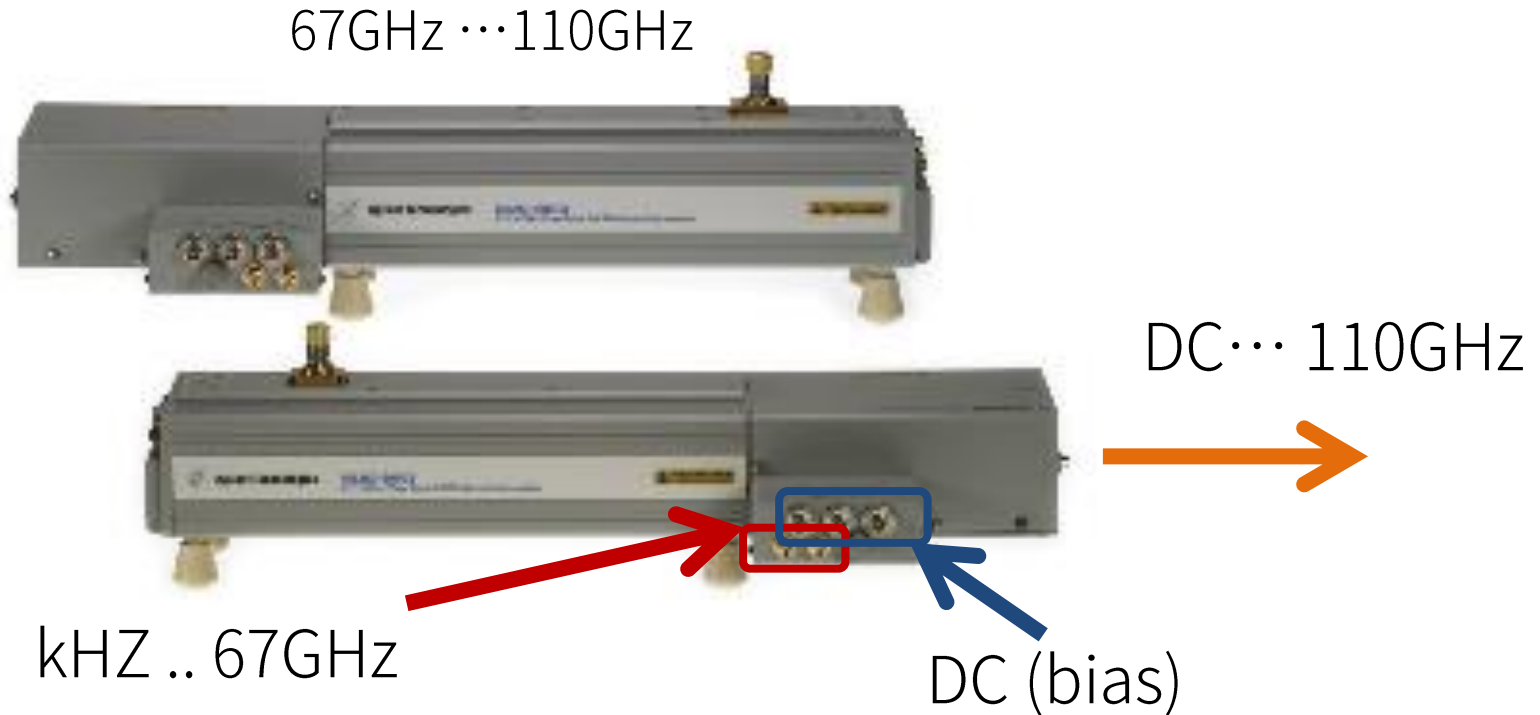
Cable Management on Positioner



Beyond 67 GHz below 110 GHz

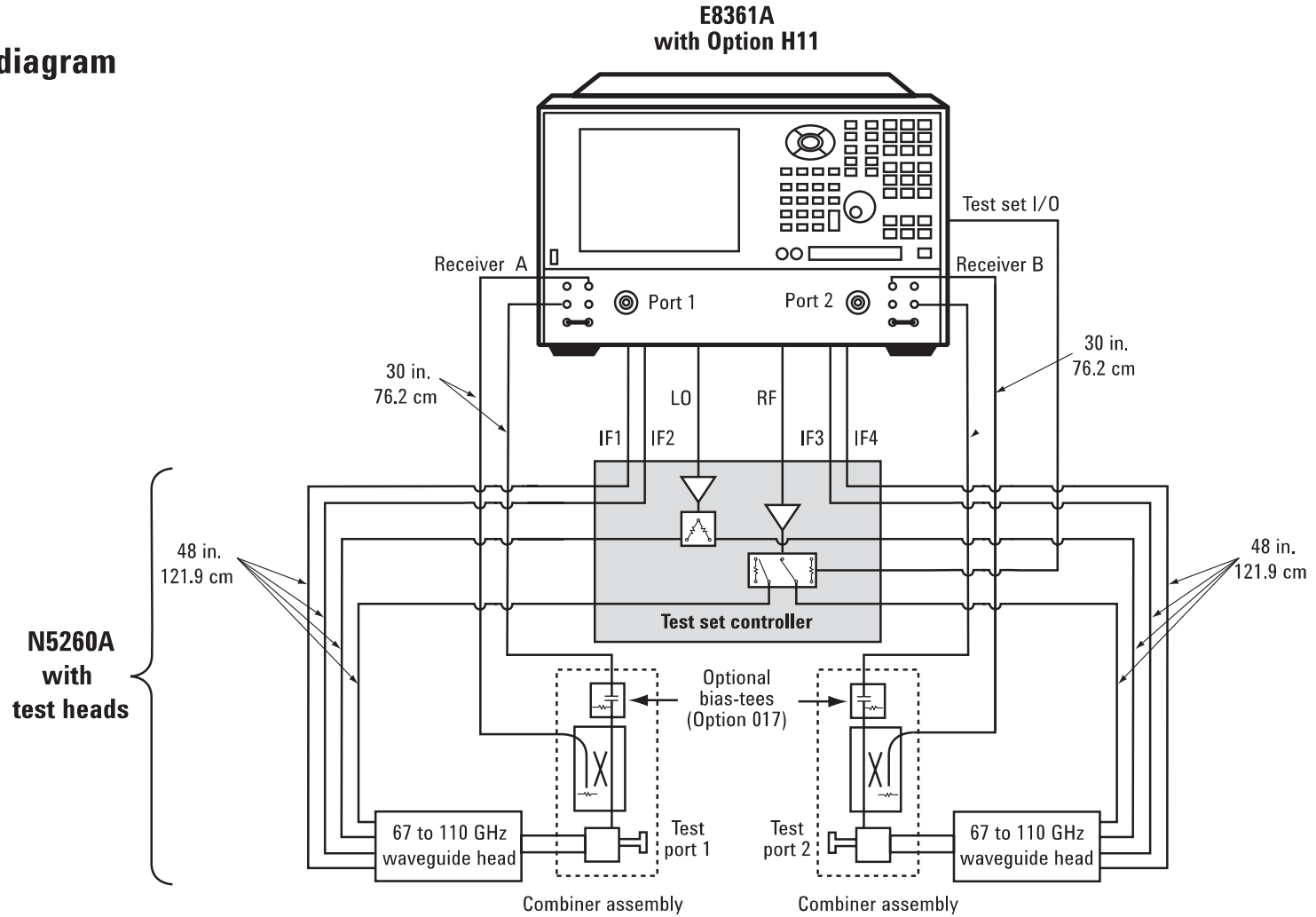
- External mm-wave heads (“extenders”)
 - From 67 GHz to 110 GHz
- Combiners
 - DC (bias source)
 - kHz···67GHz (baseband VNA)
 - 67GHz..110GHz (extenders)
- Broadband S-parameter measurement system

mm-Wave Heads

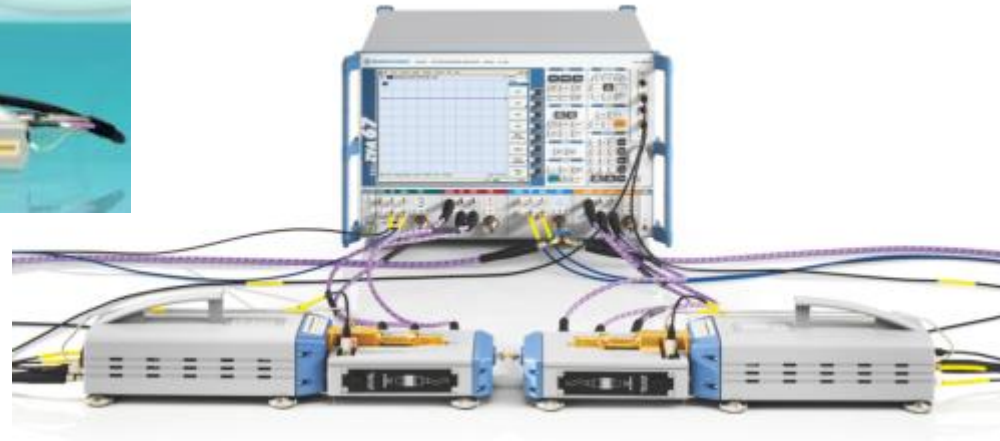


- IV/ S-Parameters measurements
- Device characterization for modeling

N5250A system block diagram



Broadband Systems











Key Wafer-Level Requirement

- mm-wave heads close to the DUT



Banded Solutions

Band	WR15	WR12 ¹	WR10 ¹	WR08	WR06	WR05	WR03	WR02.2
Waveguide Interface								
Frequency (GHz)	50-75	60-90	75-110	90-140	110-170	140-220	220-325	325-500



- Dedicated mm-wave extender per band
- Our interest: from WR-10 and beyond

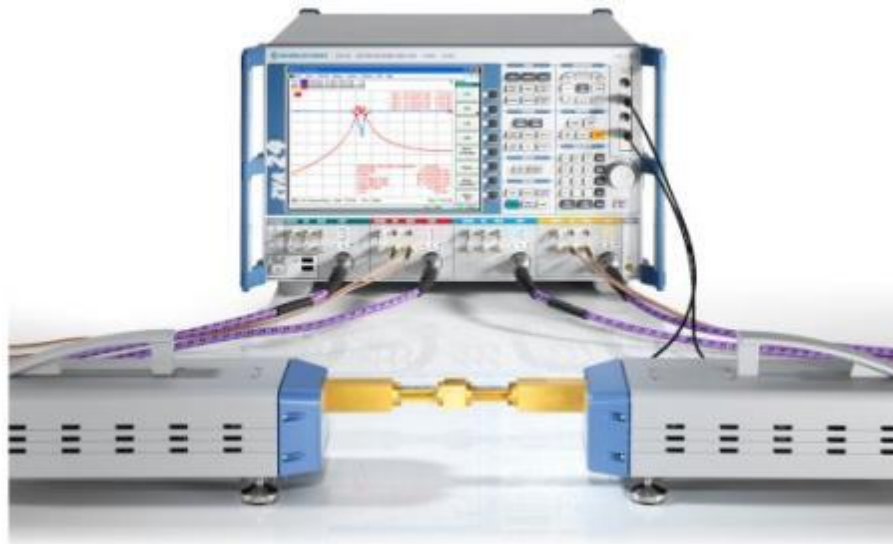
Banded Solutions: up to 1.1THz



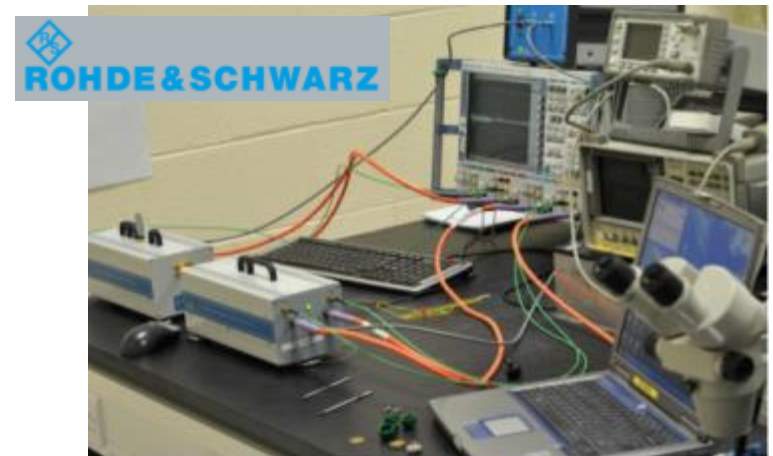
Banded Solutions: up to 500GHz



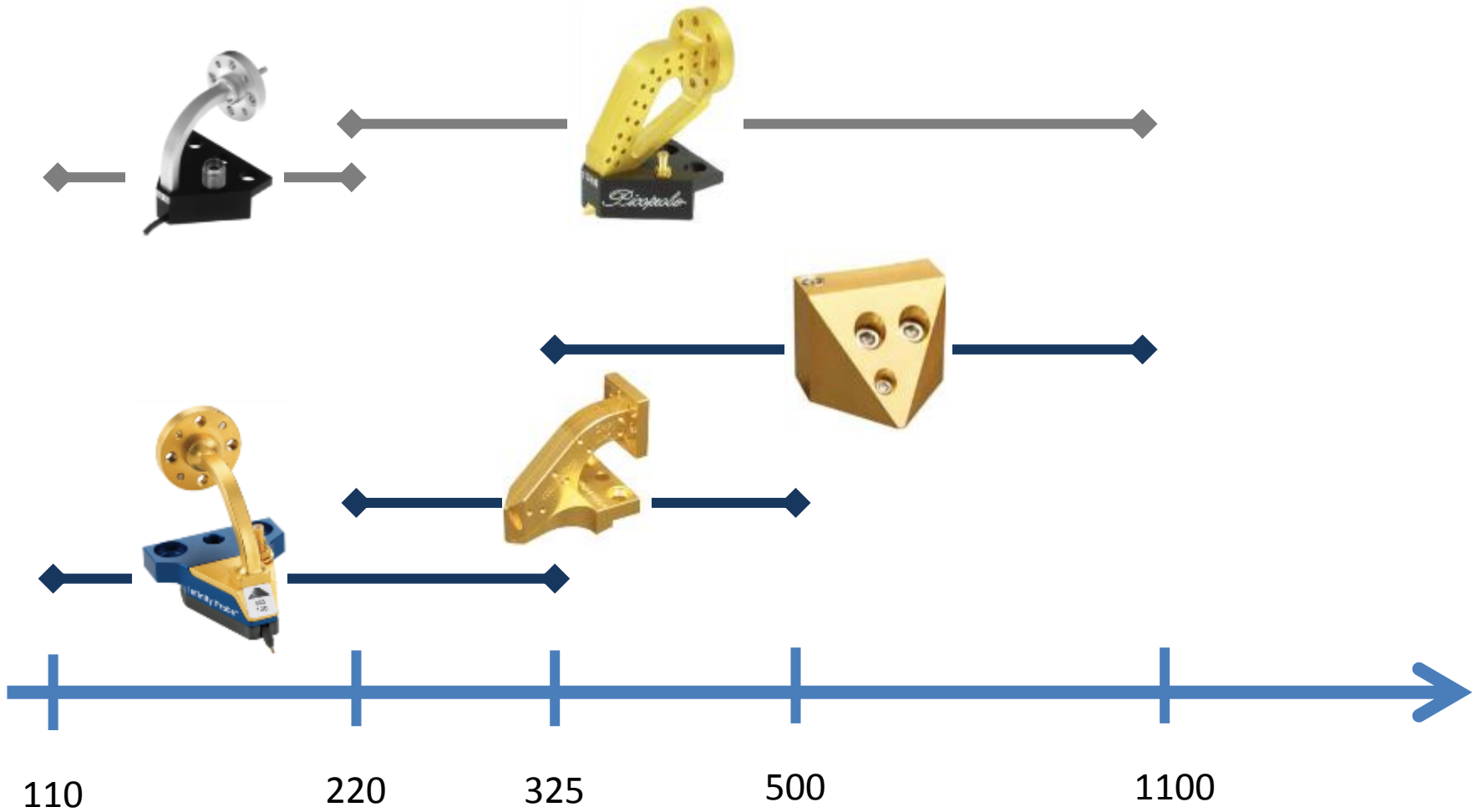
Banded Solutions: up to 500 GHz



Banded Solutions: up to 325 GHz

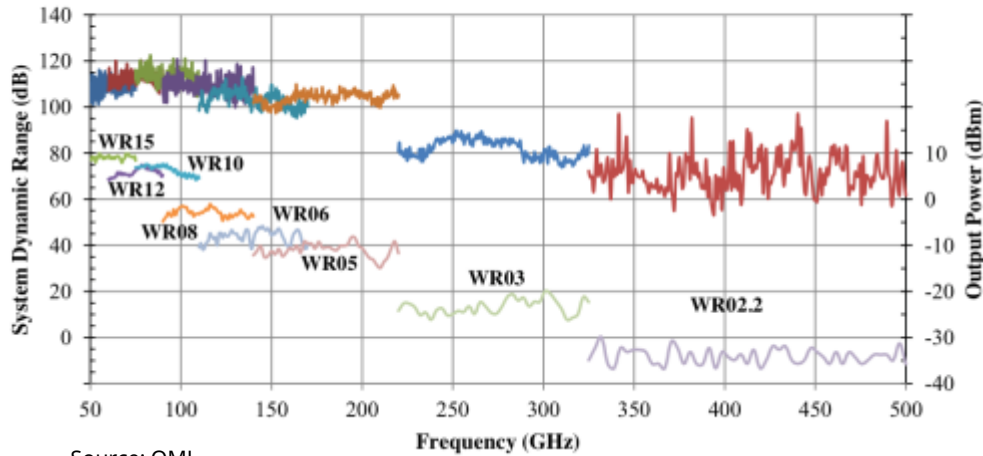


Banded Probes



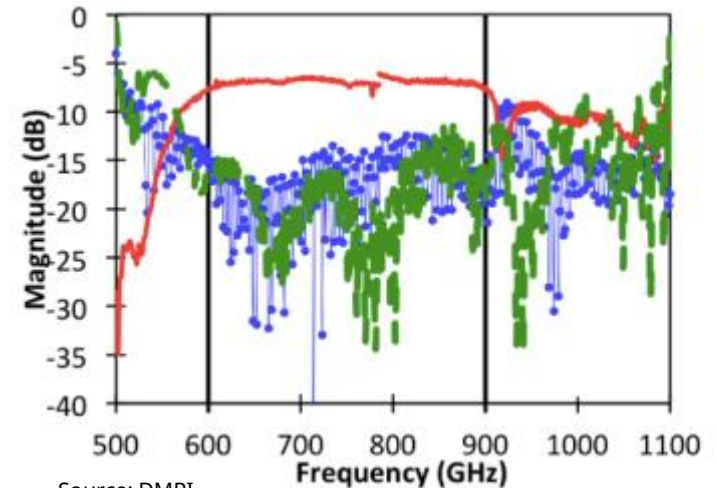
Banded Measurement Challenges

OML's VNA Frequency Extension Modules
Typical Dynamic Range & Output Power by Waveguide Band



Source: OML

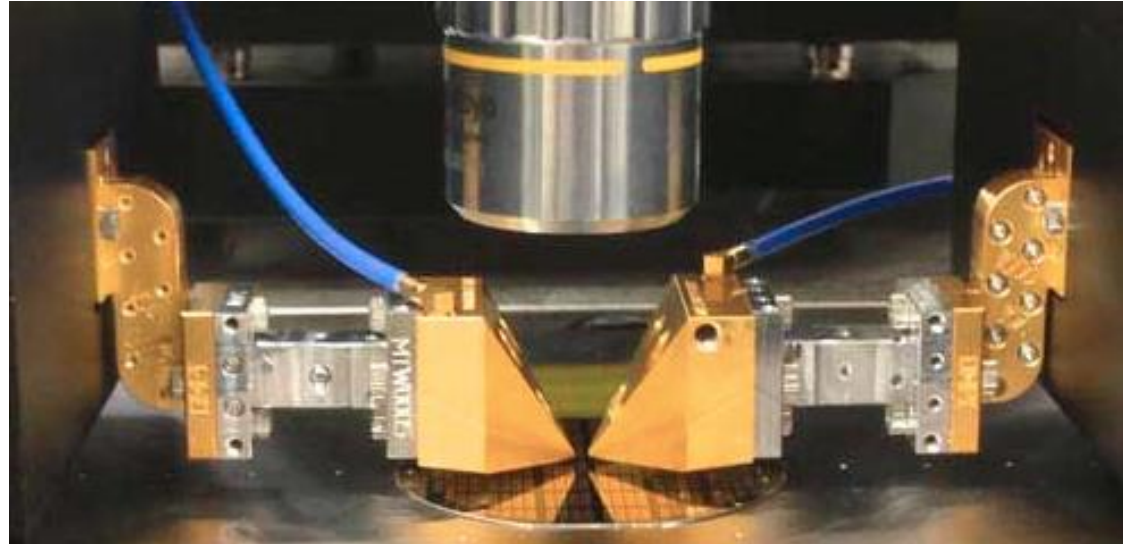
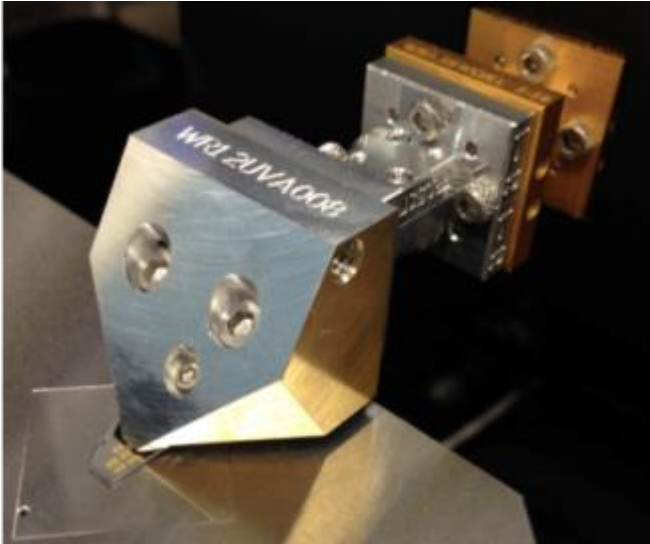
DMPI 1.1 THz Probe



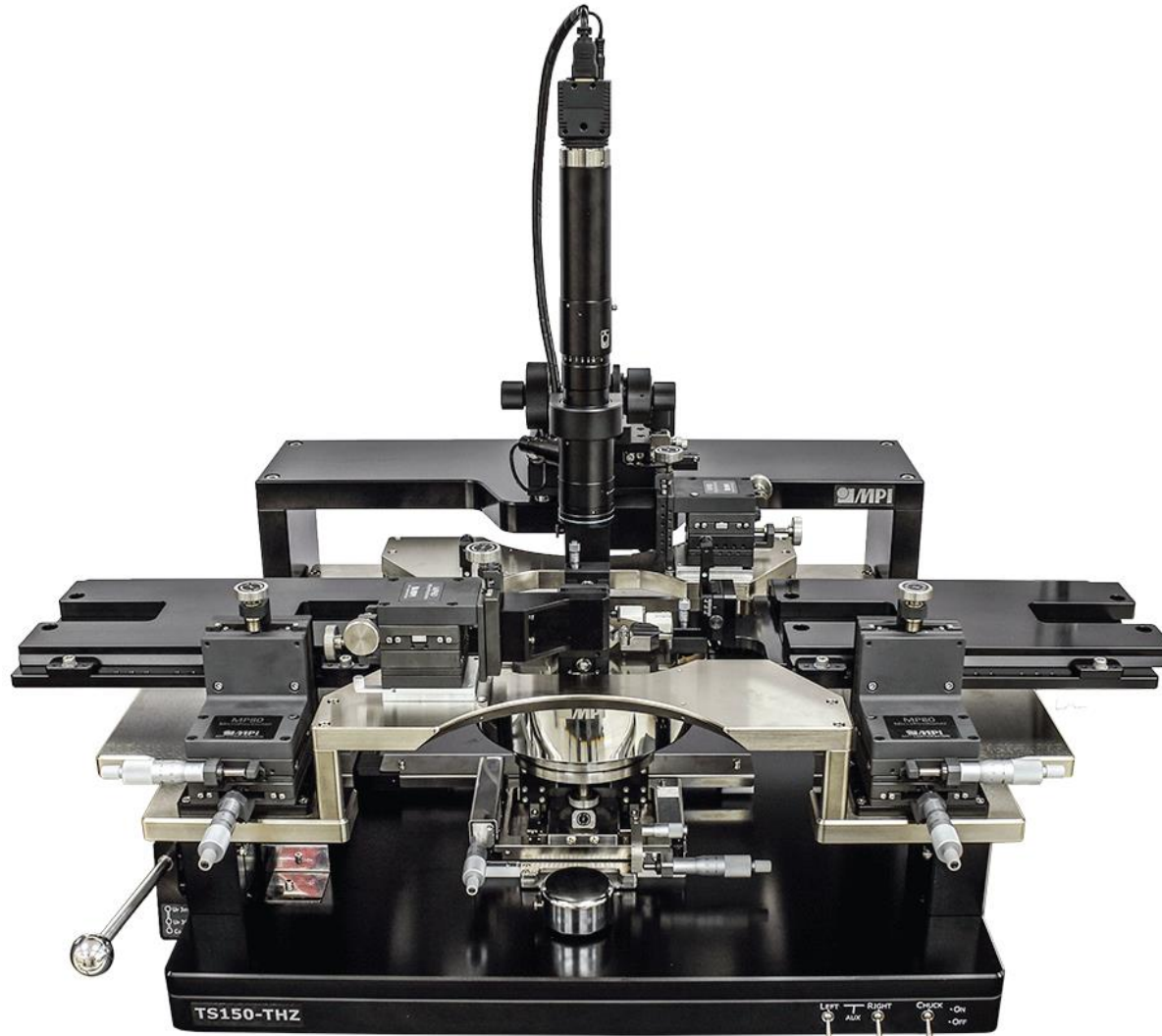
Source: DMPI

- VNA dynamic range decreases
- Waveguide losses increases
- Probe performance degrades

Probe Integration



Dedicated TS150-THZ System



MPI TS150-THZ | 150 mm Manual Probe System

The first ever, explicit designed probe system for accurate mmW and THz measurements

Microscope Mount and Movement

- Stable bridge for high quality optics
- 90° tilt for easy reconfiguration
- 50 x 50 mm linear XY movement

4-Port Bridge

- Two: in North and South
- Rectangular adjustments for RF positioners
- Designed as standard feature for DC biasing or 4-port RF
- For single DC or RF MicroPositioners

MicroPositioners

- Supports max. two, bold down large area MP80 MicroPositioners
- Unique over-travel control option
- MP80-DX option for accurate multi-line TRL calibration

Probe Platen

- Single large probe platen in rigid design
- 4 probe platen supports for max. stability
- Designed especially to accommodate large positioners for mmW and THz applications

Unique Platen Lift

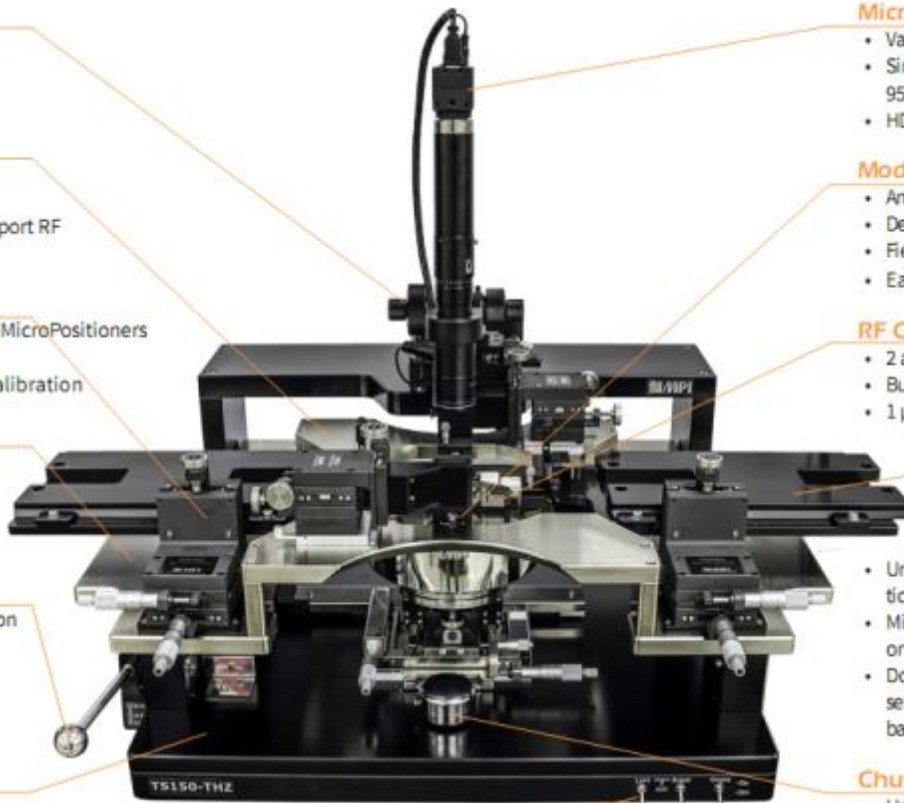
- Three discrete positions for contact, separation (300 µm) and safety loading 3 mm
- Safety lock function at loading position
- "Automated" contact position with ±1 µm repeatability for consistent contact quality

Small Footprint

- Designed for bench top use
- Comes with vibration absorber base
- Low profile design for maximum usability
- Ideal for mmW, THz and load pull applications

Front Mounted Vacuum Control

- Easy access
- Clearly marked



Microscope and Optics Options

- Various optics options available
- Single tube MPI SZ10, MZ12 with up to 12x zoom and 95 mm working distance
- HDMI cameras with up to 5 MP available

Modular Chucks

- Ambient or hot only chucks
- Dedicated RF or mmW designs
- Field upgradable for reduced cost of ownership
- Easy switch between center and small wafer size control

RF Calibration

- 2 auxiliary chucks for calibration substrates
- Built-in ceramic for accurate calibration
- 1 µm flatness for consistent contact quality

MP80 Integration Modules

- 2 options for waveguide or coax application
- Universal large area platforms for integrating various frequency extenders up to 1.1 THz
- Unique air-spring design for balance weight compensation and max. stability
- Micrometer screws for fine waveguide probe leveling on the platforms
- Dove-tail interface for dedicated adaptations for easy setup and switching between different frequency bands

Chuck XYZ Stage Movement

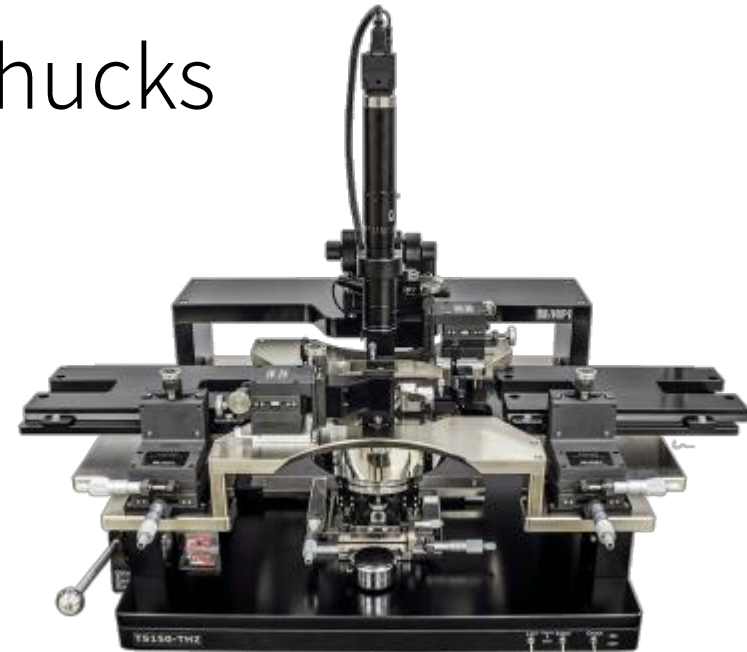
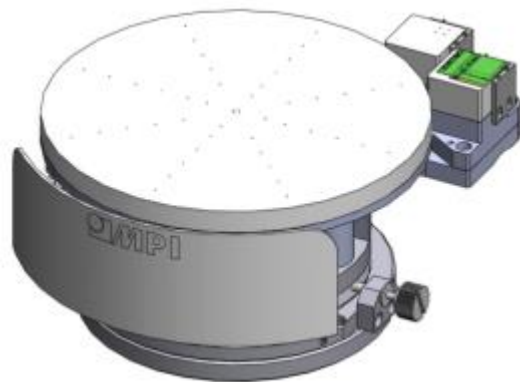
- Unique puck control air bearing stage for quick one-hand operation
- Large vacuum base for max. stability
- 175 x 225 mm XY fast movement
- 25 x 25 mm micrometer fine XY adjustment
- 10 mm fine Z chuck adjustment
- ±5° Theta fine adjustment
- Extra wide Y-range for easy loading

Available Options

- Various adaptations for different frequency extenders
- Vibration isolation table
- Table with integrated rack for thermal controller, computer and keyboard push tray
 - Dual monitor stand option
 - Instrument shelf option

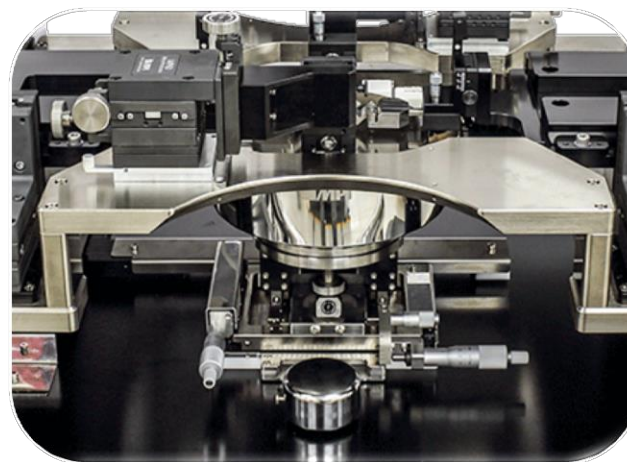
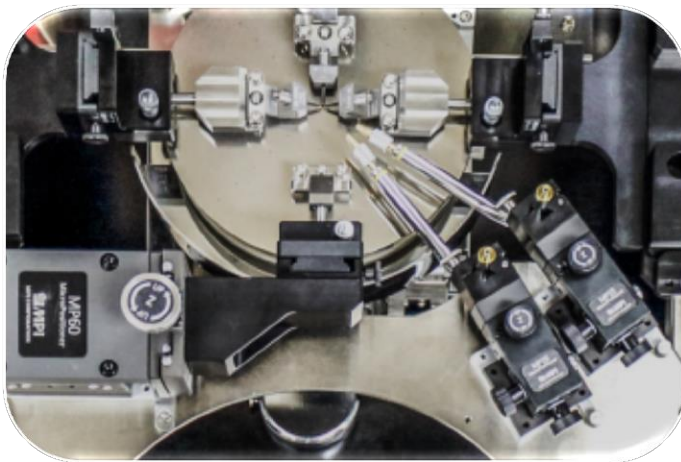
Designed for unsurpassed stability

- Large area stainless steel probe platen
- Probe platen at lowest possible position
- No chuck elevation
- Ceramic chuck and AUX chucks



Dedicated Design for THz Application

- Support R&S and all other extenders:
 - up to 1.1THz
- 4-Port as part of the base system
- Fine Z chuck



THANK YOU
FOR YOUR ATTENTION

For more information, please visit:
www.mpi-corporation.com